

Using Large-Signal Measurements for Transistor Characterization and Model Verification in a Device Modeling Program

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Dominique Schreurs¹, and Bart Nauwelaers¹

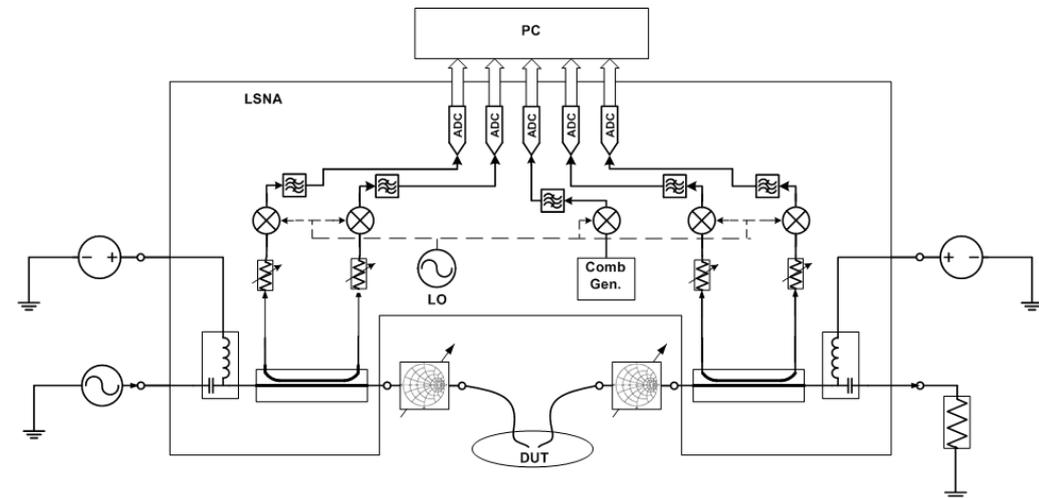
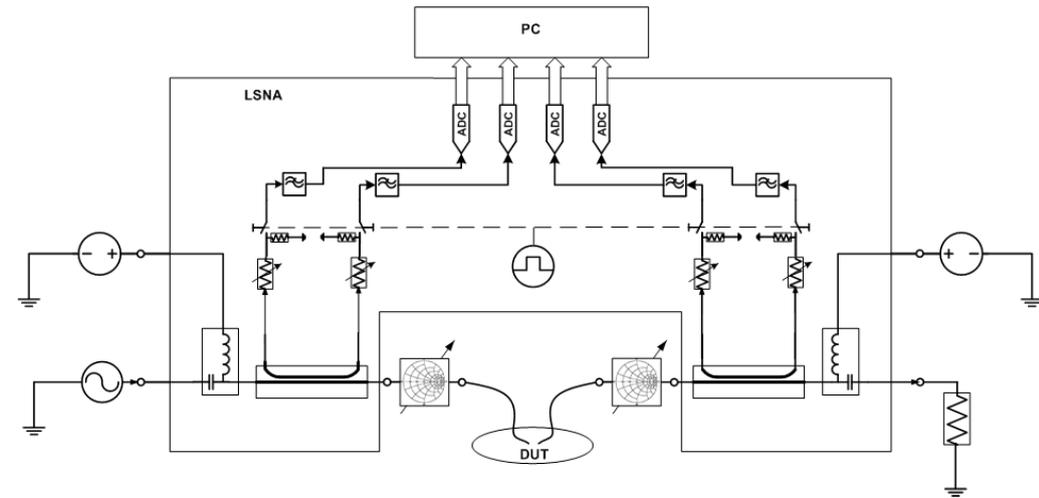
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- Introduction
- Large-signal measurement data in a device modeling program
 - Example: IC-CAP
- Transistor characterization
 - Example: MOSFET
- Model verification
 - Example: Angelov model
- Results
- Conclusions

- Large-signal network analyzer (LSNA)
 - Amplitude and phase of all harmonics and intermods up to 50 GHz
 - Realistic signals:
 - 1-tone, 2-tone, N-tone up to +40 dBm
 - DC, small-signal, large-signal behavior
 - Non-50 Ω environment
 - Sampler/Mixer-based



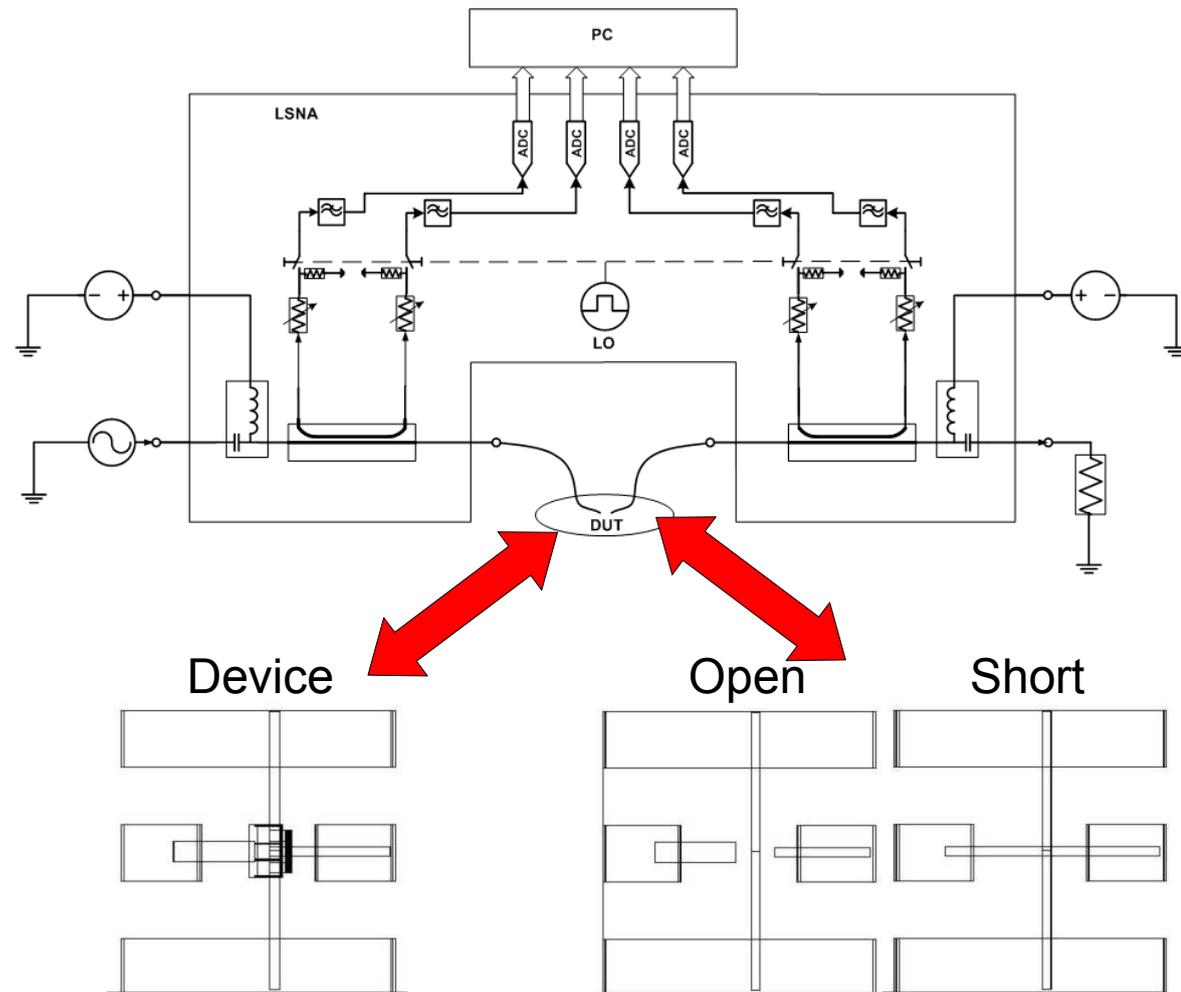
- Large-signal on-wafer measurements

- Device:

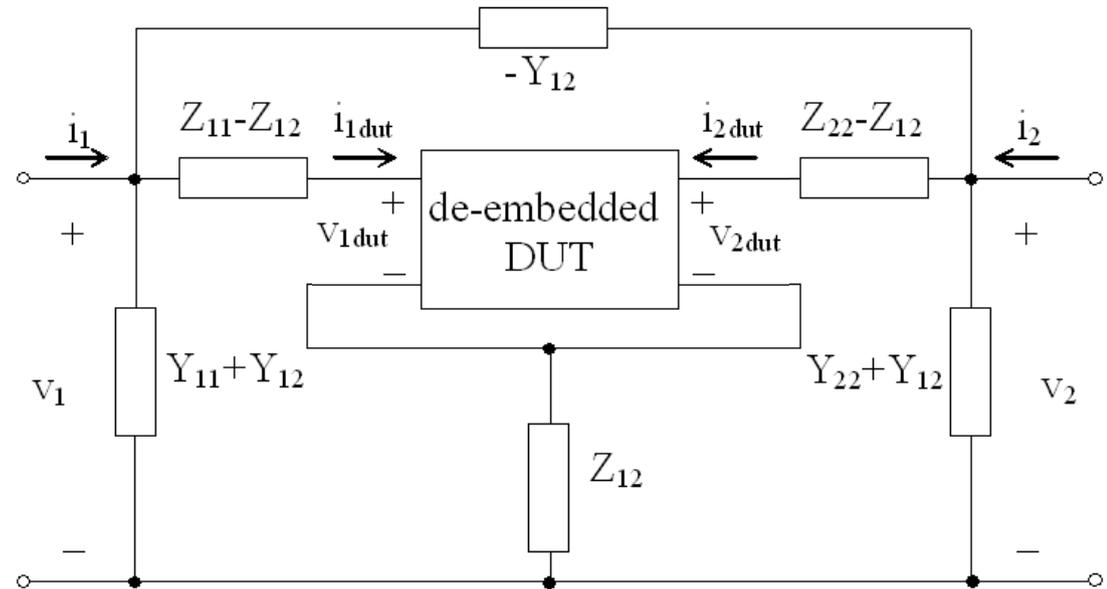
- Frequency sweep
- RF power sweep
- DC bias sweep

- De-embedding structures:

- Frequency sweep



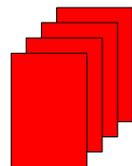
- Large-signal on-wafer measurements
- Data processing
 - De-embedding
 - Transformation to the program specific format



$Y_{ij} \rightarrow$ Y-parameters of open

$Z_{ij} \rightarrow$ Z-parameters of short, after de-embedding of open effects.

MDM files



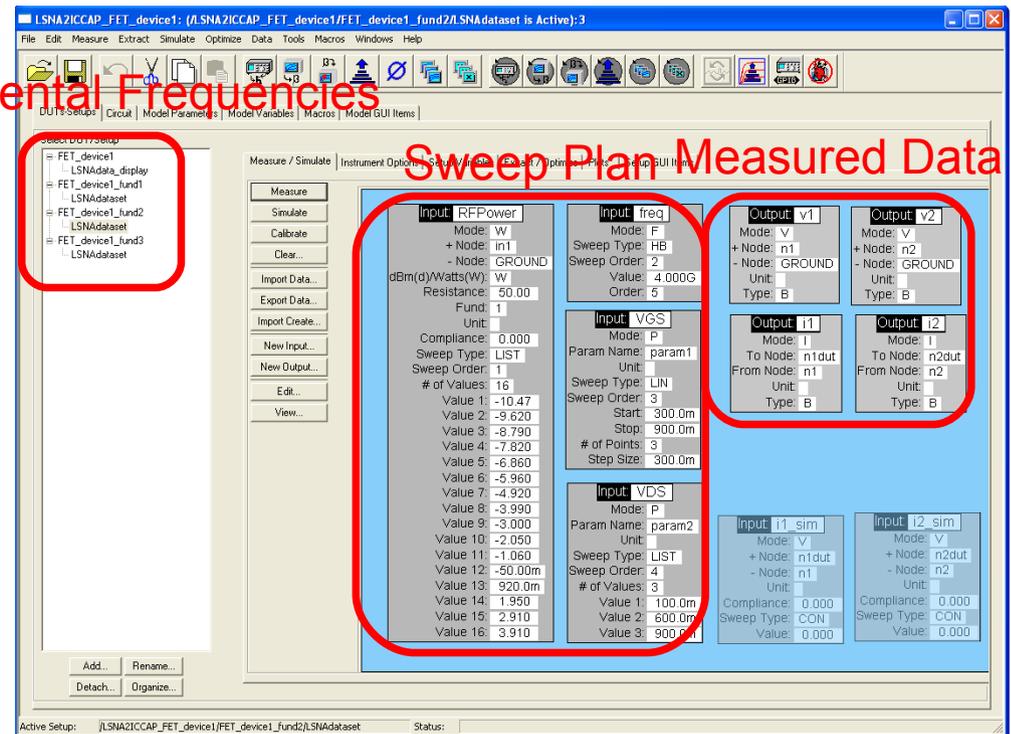
$$\begin{aligned}
 i_{1dut} &= i_1 - v_1(Y_{11} + Y_{12}) - (v_2 - v_1)Y_{12} = i_1 - v_1Y_{11} - v_2Y_{12} \\
 i_{2dut} &= i_2 - v_2(Y_{22} + Y_{12}) - (v_1 - v_2)Y_{12} = i_2 - v_2Y_{22} - v_1Y_{12} \\
 v_{1dut} &= v_1 - i_{1dut}Z_{11} - i_{2dut}Z_{12} \\
 v_{2dut} &= v_2 - i_{2dut}Z_{22} - i_{1dut}Z_{12}
 \end{aligned}$$

- Large-signal on-wafer measurements
- Data processing
- Implementation in the device modeling program
 - Measured data

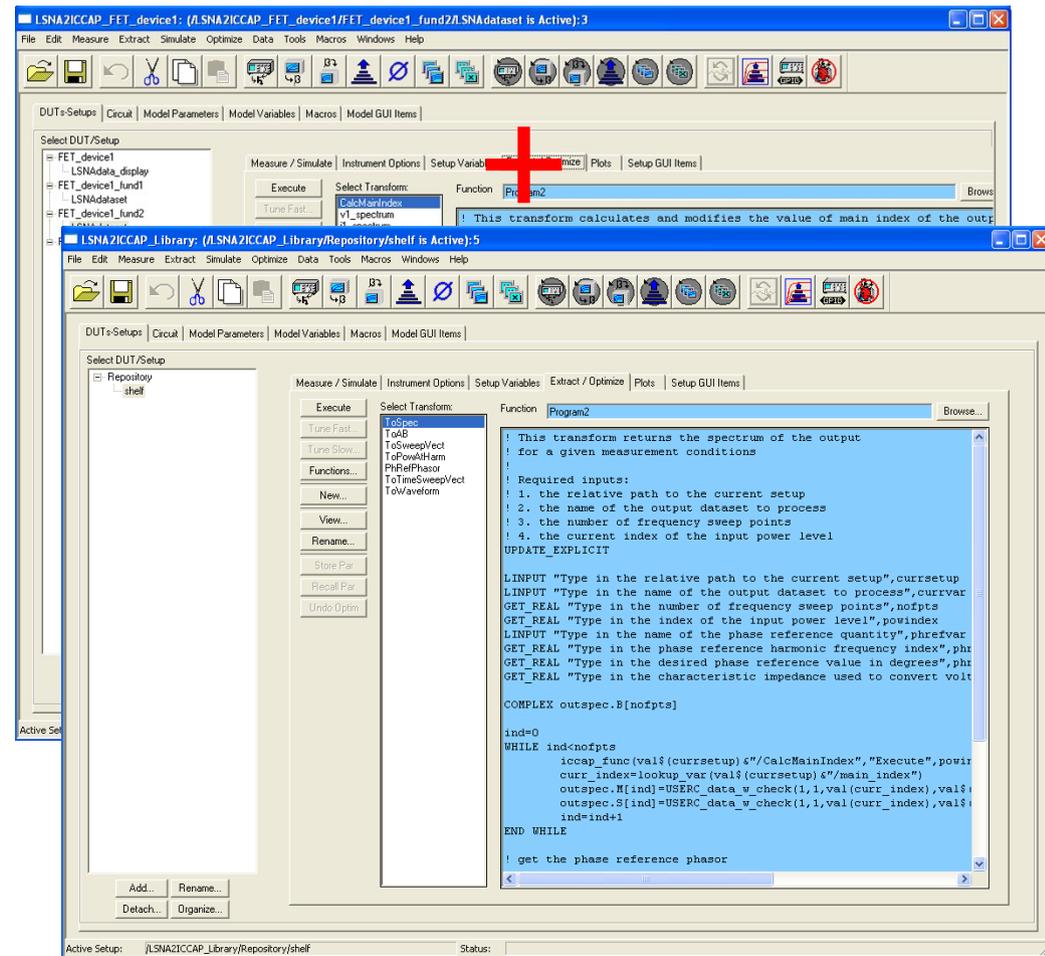


Fundamental Frequencies

Sweep Plan Measured Data



- Large-signal on-wafer measurements
- Data processing
- Implementation in the device modeling program
 - Measured data
 - Data processing routines



- Large-signal on-wafer measurements
- Data processing
- Implementation in the device modeling program
 - Measured data
 - Data processing routines
 - Link to simulator

```

; Here comes the main part related to the measurement-based excitation.
; These commands are passed directly to the ADS hpeesofsim simulator

; Define variables
#echo Zo=50

#echo param1=0.3
#echo param2=0.1

; Add DAC with the large-signal measurement data

#use lib "c:\", "DAC"
#echo DAC:lsna File="C:/users/default/lsna2iccap/FETdemo/FET_device1_fund2_v1.cit" \
#echo Type="citi" InterpMode="value_lookup" \
#echo iVar1="VDS" iVar11=param2 \
#echo iVar2="VGS" iVar12=param1 \
#echo iVar3="Freq" iVar13=freq \
#echo iVar4="RFPower" iVar14=pin \

; Access measured variables
#echo v1=file(lsna,"v1")
#echo i1=file(lsna,"i1")
#echo v2=file(lsna,"v2")
#echo i2=file(lsna,"i2")
#echo a1=(v1+Zo*i1)/2
#echo a2=(v2+Zo*i2)/2

; Add voltage sources
;#echo V_Source:vport1 n2 0 V[1]=0 V_A11=v1 FundIndex=1
;#echo V_Source:vport2 n4 0 V[1]=0 V_A11=v2 FundIndex=1

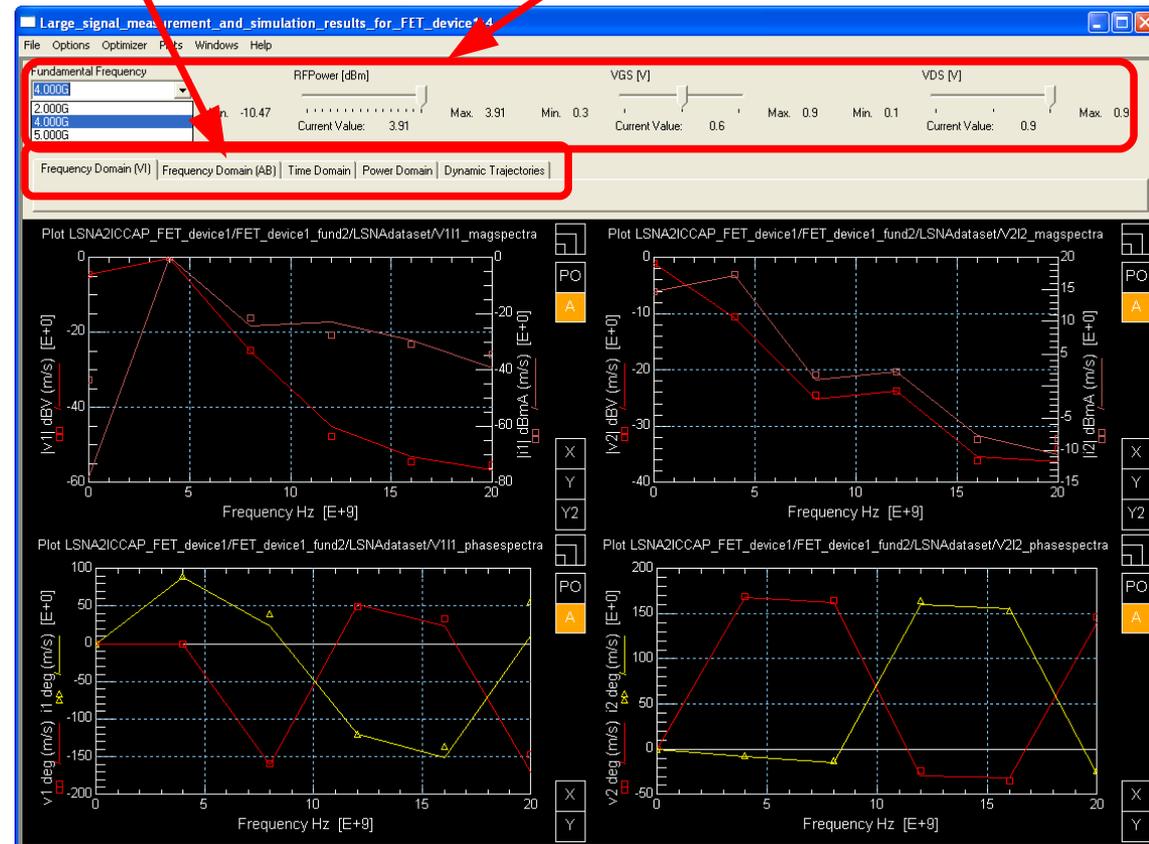
; or add power sources
#echo R:Rport1 n102 n2 R=50
#echo V_Source:pinport1 n102 0 V[1]=0 V_A11=2*a1 FundIndex=1
#echo R:Rport2 n104 n4 R=50
#echo V_Source:pinport2 n104 0 V[1]=0 V_A11=2*a2 FundIndex=1
    
```

+ CITI files

- Large-signal on-wafer measurements
- Data processing
- Implementation in the device modeling program
 - Measured data
 - Data processing routines
 - Link to simulator
 - Graphic user interface

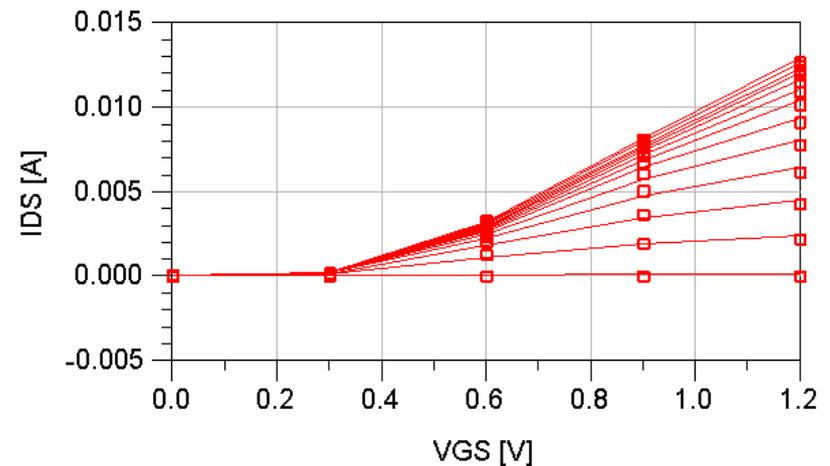
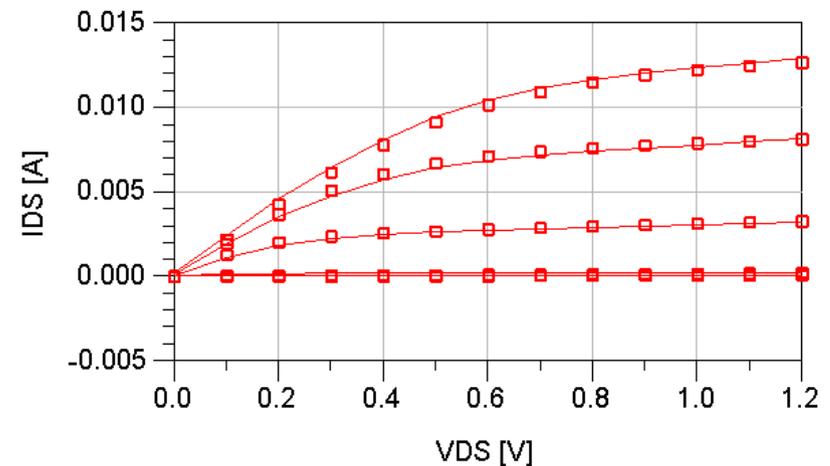
Selecting display domain

Selecting measurement conditions



- On-wafer DUT:
 - MOSFET
 - Open & Short de-embedding structures

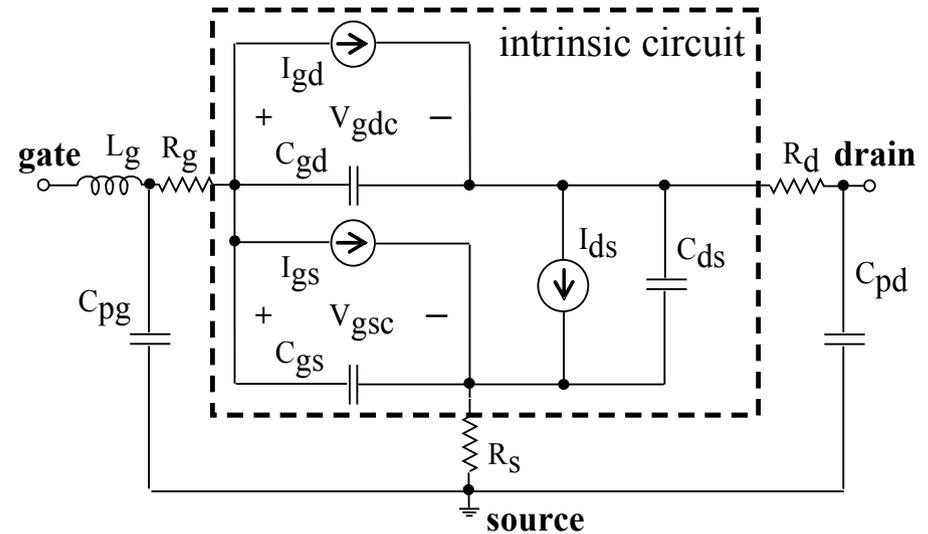
- LSNA measurements:
 - f_0 : 2, 4, 5 GHz
 - P_{in} : -10 \rightarrow +4 dBm
 - V_{GS} : 0.3, 0.6, 0.9 V
 - V_{DS} : 0.1, 0.6, 0.9 V



- Angelov MOSFET model:

- Neglected self-heating and intrinsic non quasi static effects,
- Capacitance mode,
- Extracted from DC and S-parameter measurements

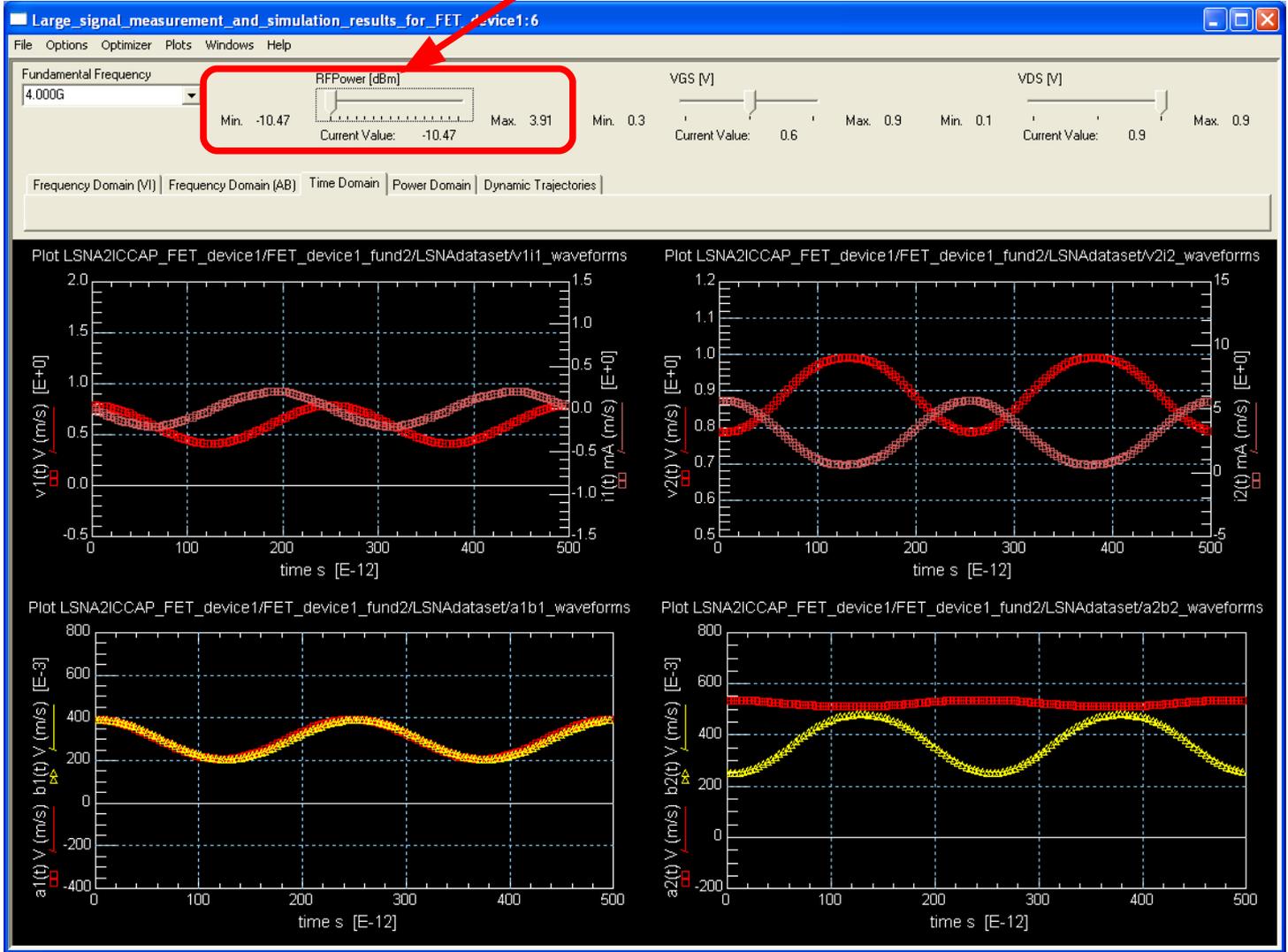
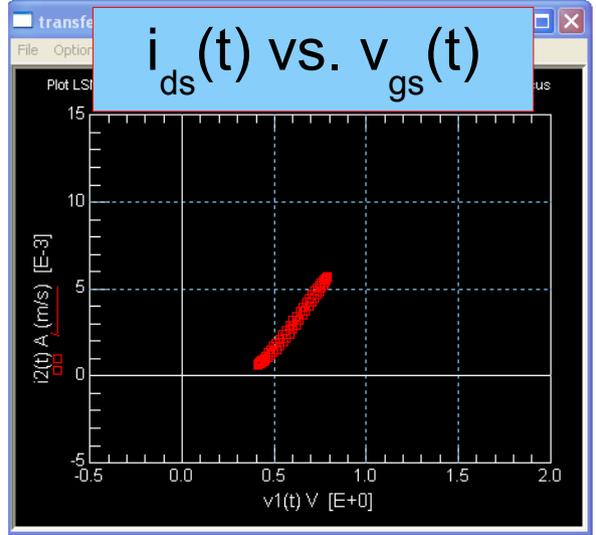
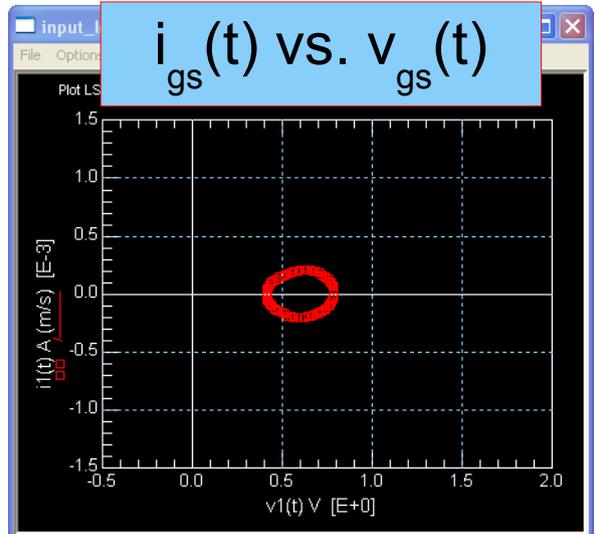
- Tuned around:
 $V_{GS} = 0.6 \text{ V}$, $V_{DS} = 0.9 \text{ V}$,
 $f_0 = 4 \text{ GHz}$



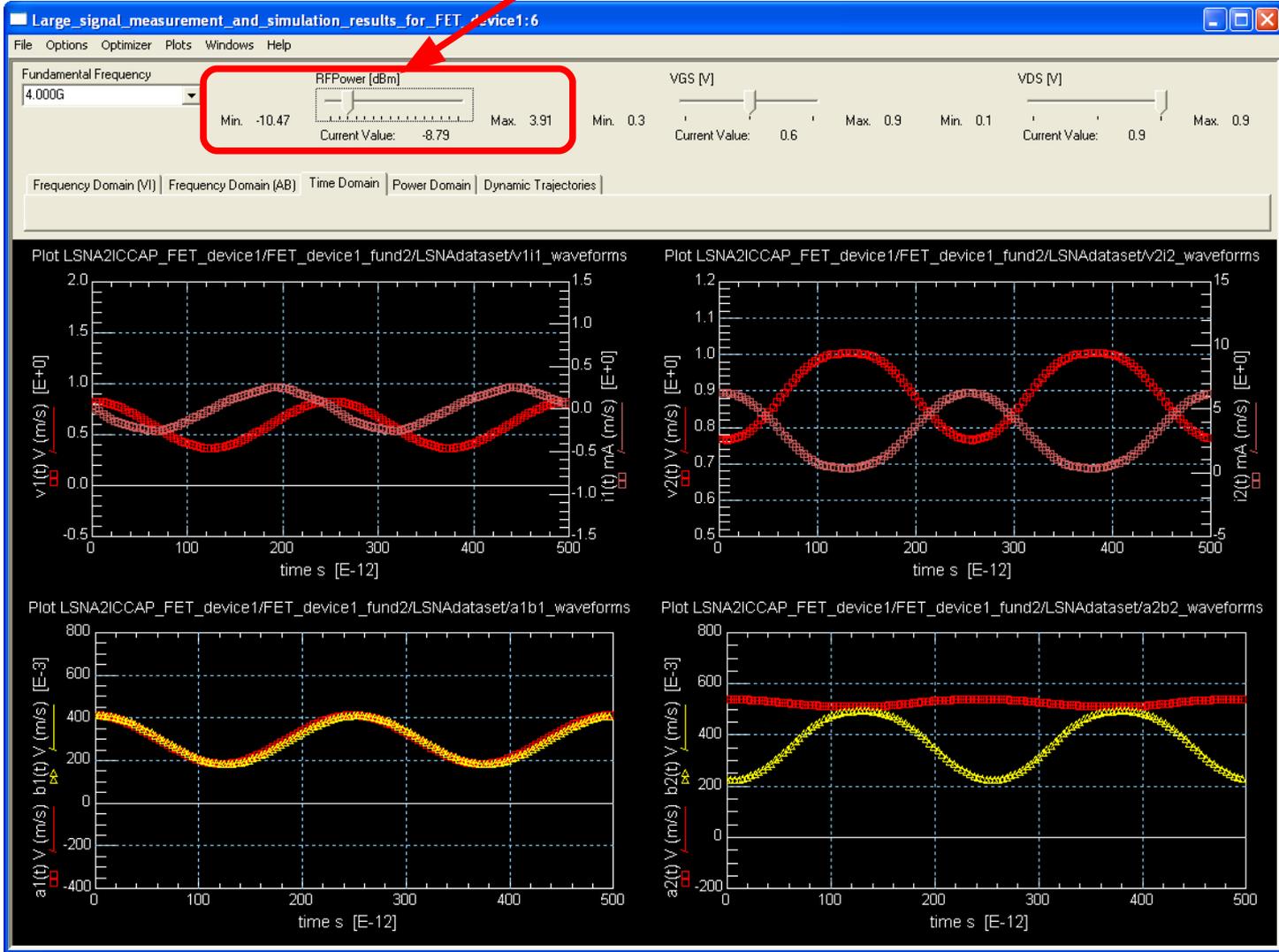
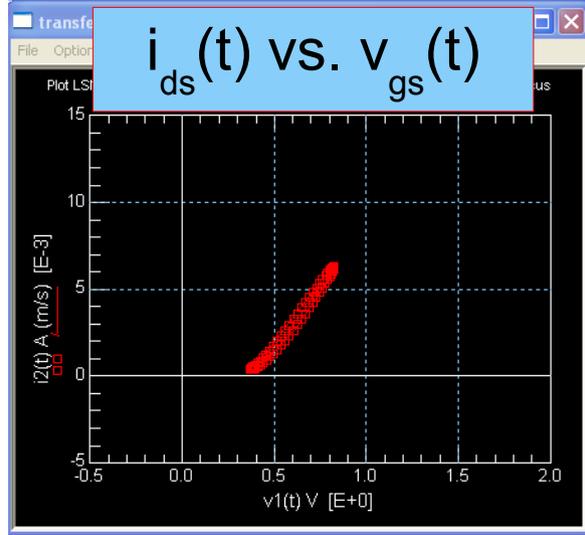
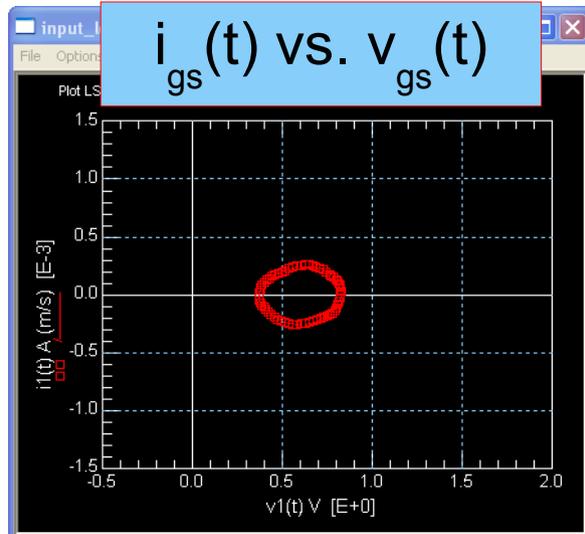
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model AngelovM1 Angelov B1=0 P31=0.54852 Rcmin=0kOhm
Idsmode=1 B2=3.92 P40=1.2 Rc=0kOhm
Igmmod=1 Lsb0=0 P41=1.71519 Crf=35.3284fF
Capmod=1 Vtr=4 P111=0.001 Rcin=0kOhm
Ipk0=0.0066 Vsb2=0 Ij=0.0025 Crfin=0fF
Vpks=0.84 Cds=28.331fF Pg=0.0002 Rth=50
Dvpks=0.027 Cgspi=2.6fF Vjg=0.9 Cth=0
P1=2.5 Cgs0=5fF Rg=22.4 Tcipk0=0
P2=0.1 Cgdpi=4.5446fF Rd=10.7 Tcpi=0
P3=6.2 Cgd0=5.06055fF Rs=11.2 Tccgs0=0
Alphar=2.5 Cgdpe=0fF Ri=0 Tccgd0=0
Alphas=0.5 P10=1 Rgd=0 Tclsb0=0
Vkn=0.5 P11=1.71519 Lg=0pH Tcr=0
Lambda=0.1 P20=0.2 Ld=0 Tccrf=0
Lambda1=0.07 P21=0.54852 Ls=0 Tnom=25
Lvg=0 P30=0.25 Tau=0ps
    
```

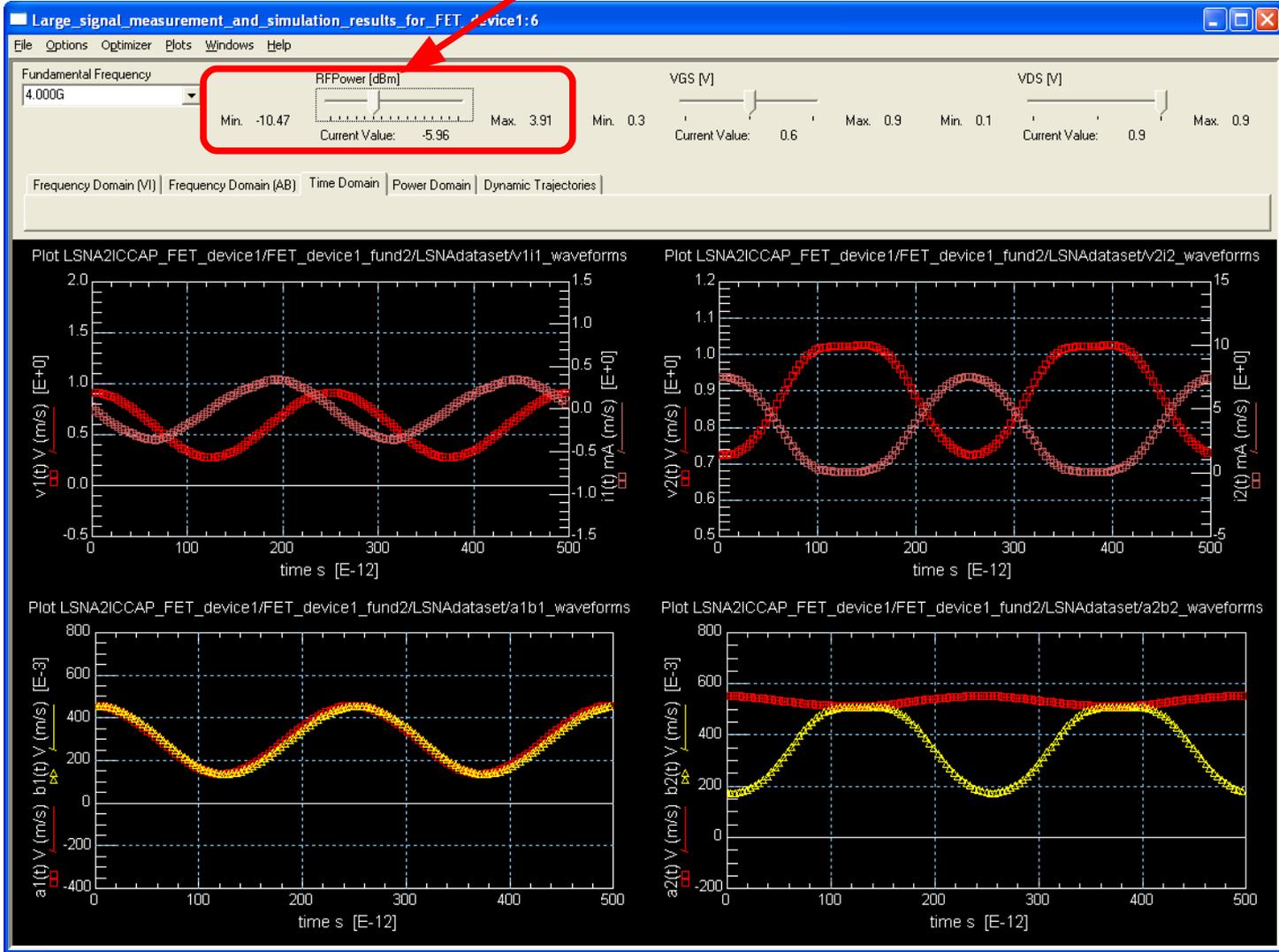
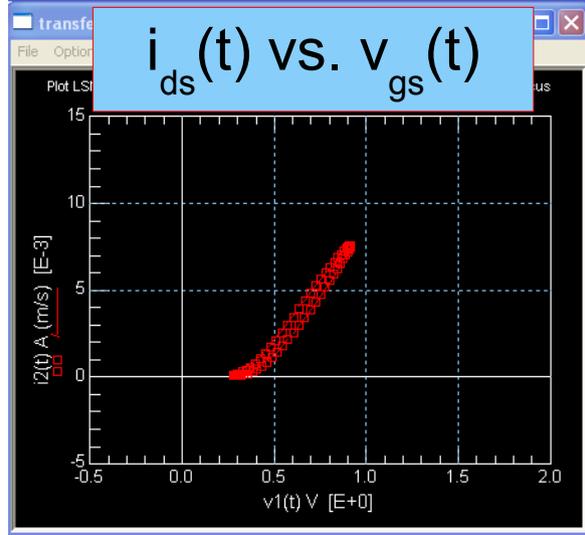
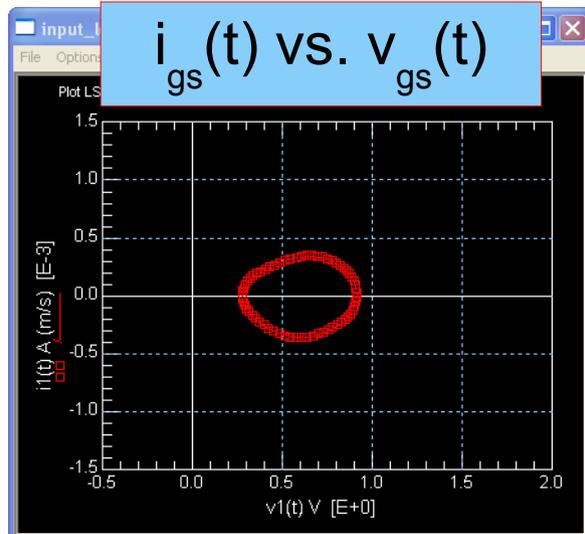
$f_0 = 4 \text{ GHz}$, $V_{GS} = 0.6 \text{ V}$, $V_{DS} = 0.9 \text{ V}$, **RF power: -10.47 \rightarrow +3.91 dBm**



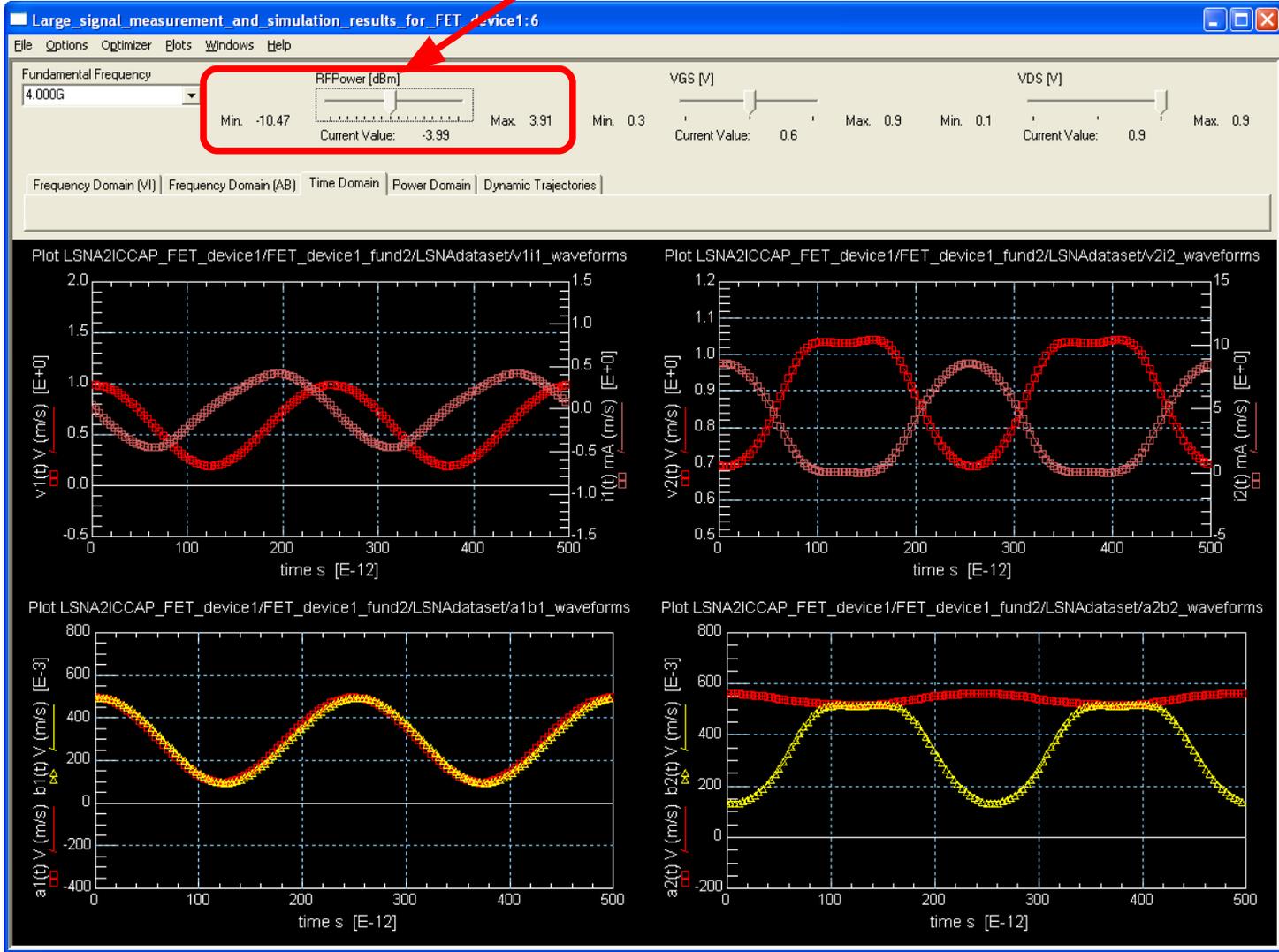
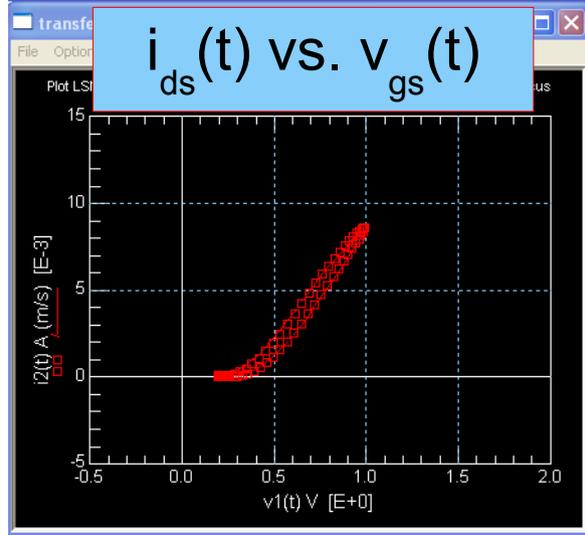
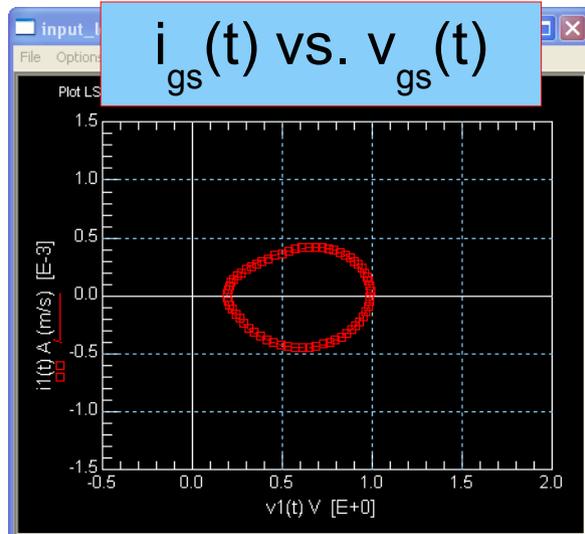
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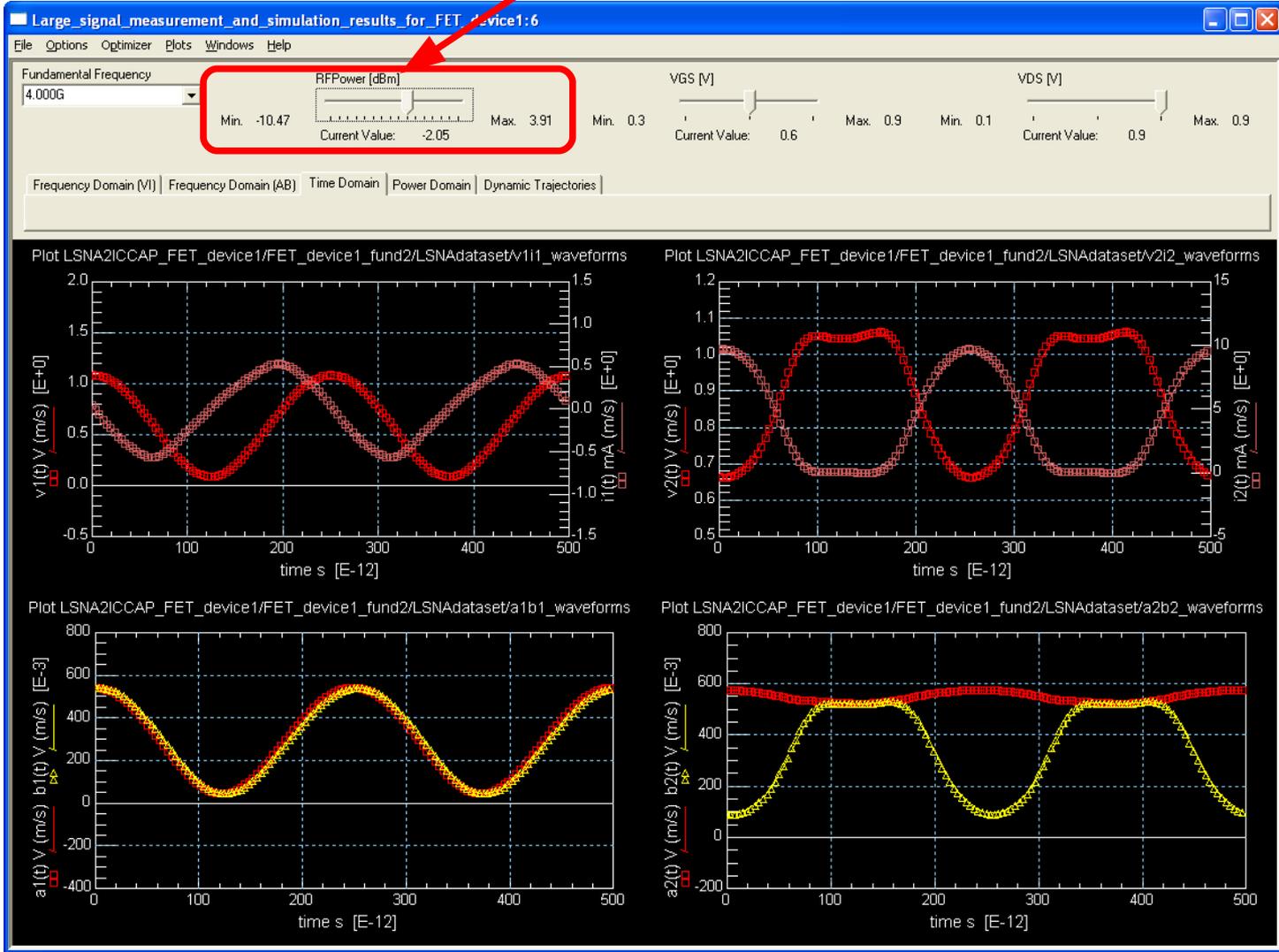
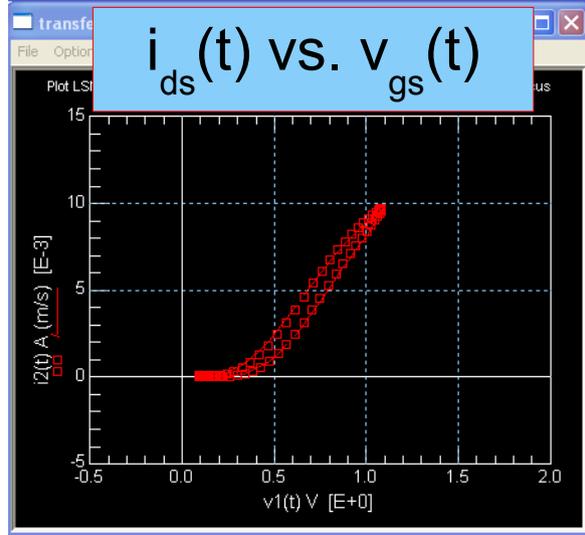
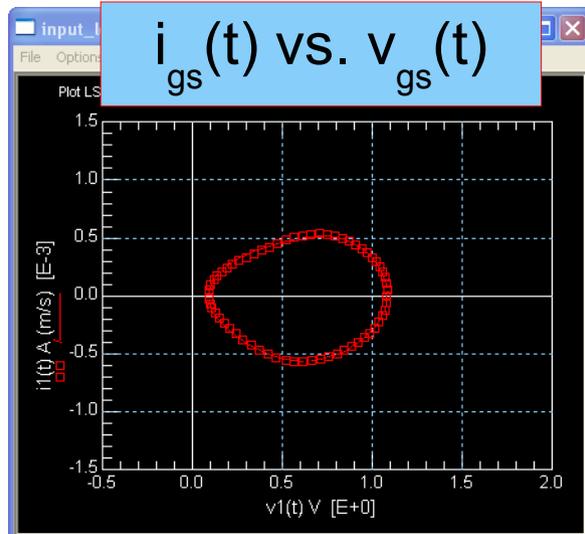
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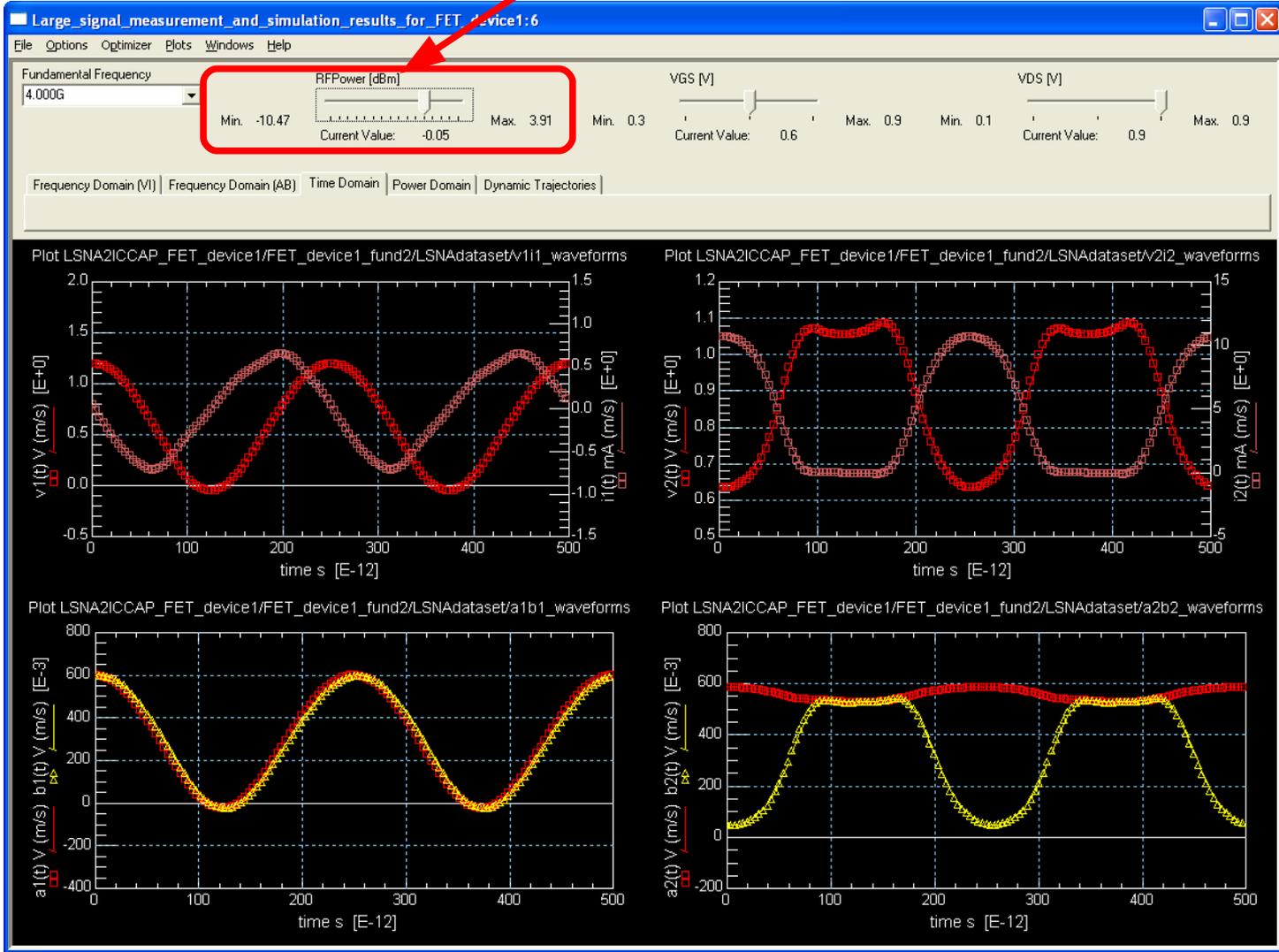
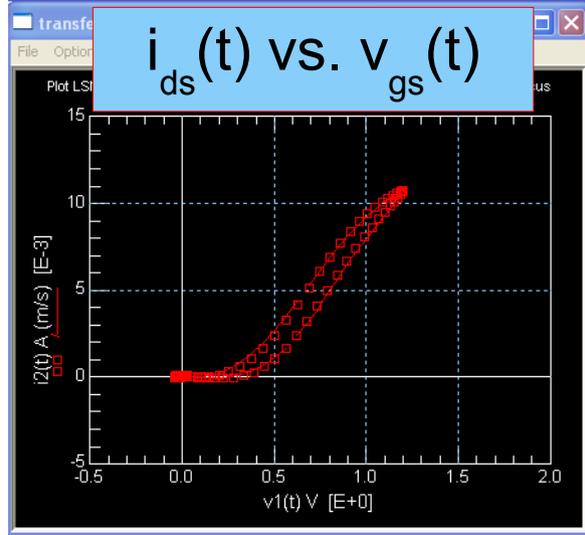
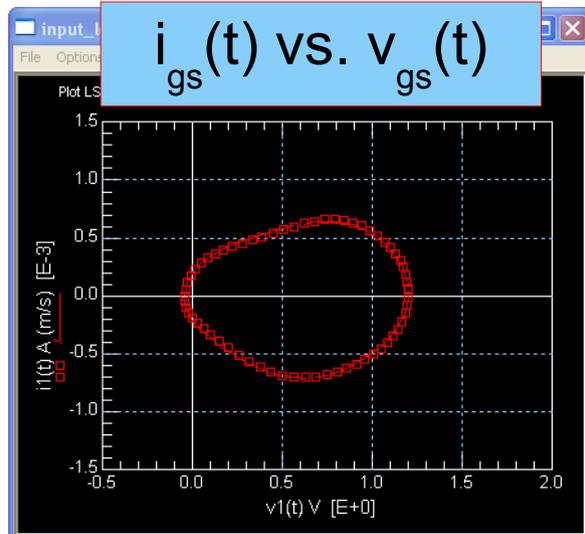
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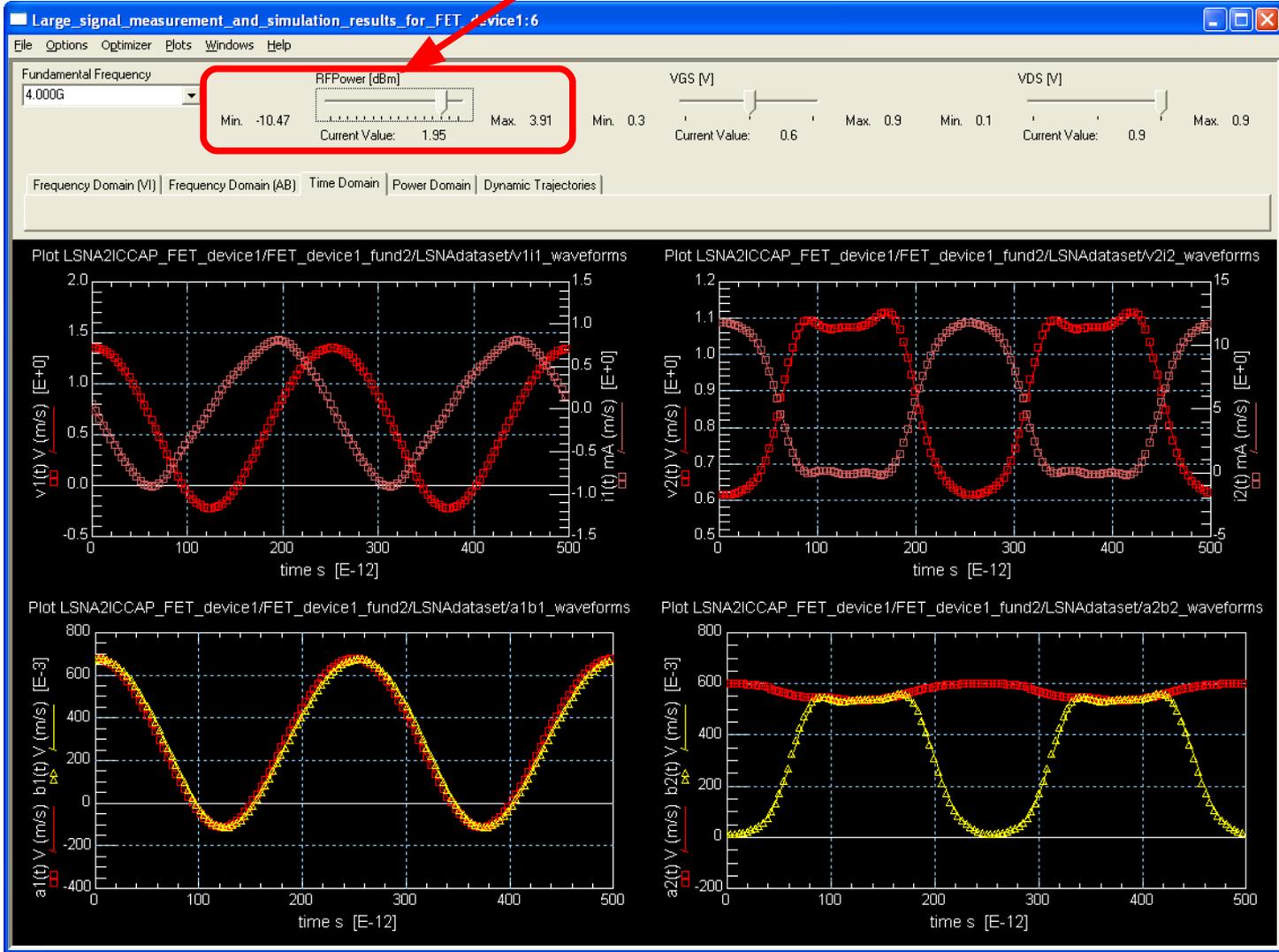
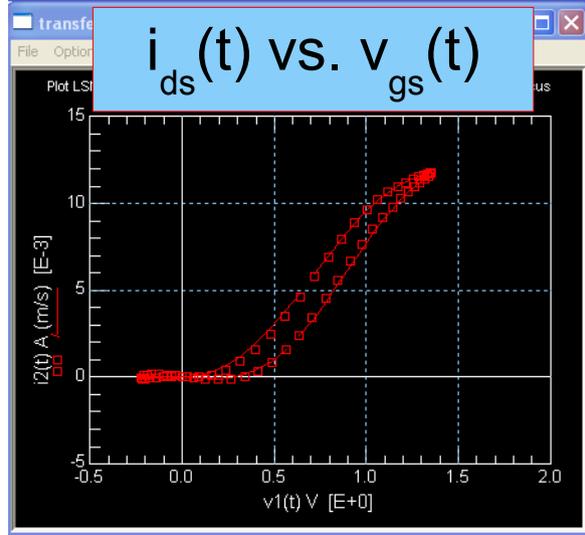
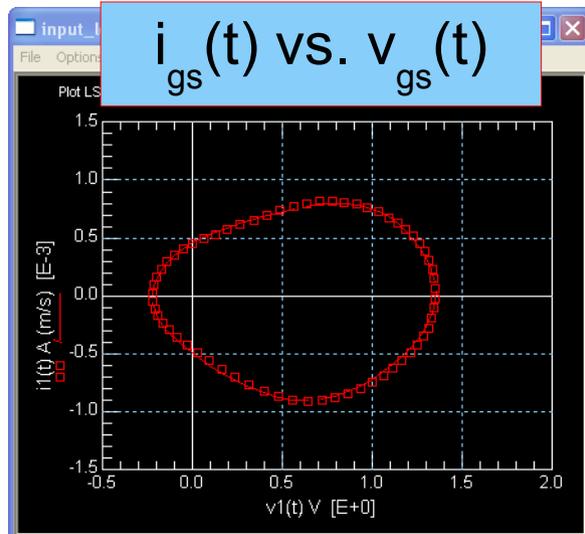
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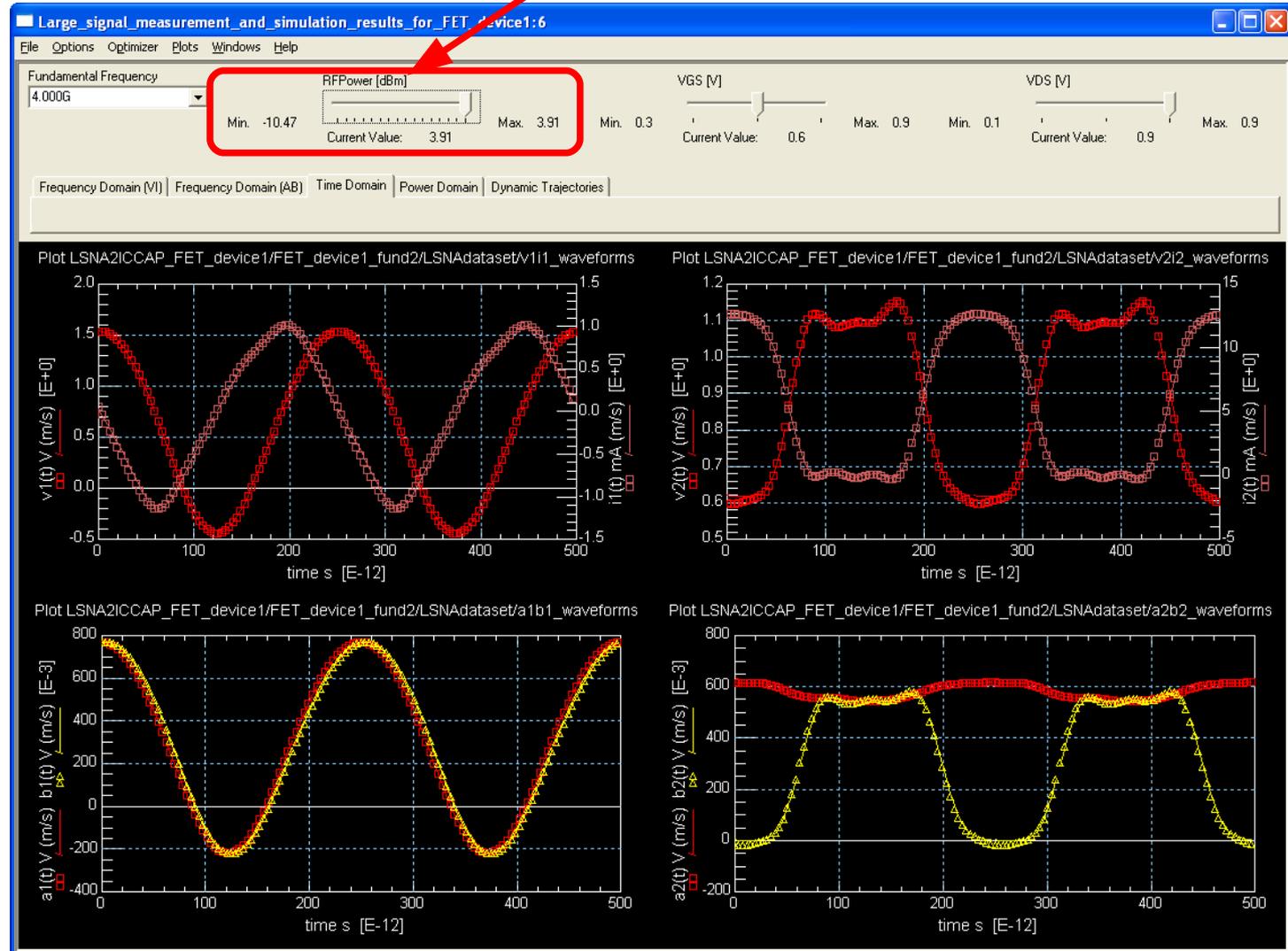
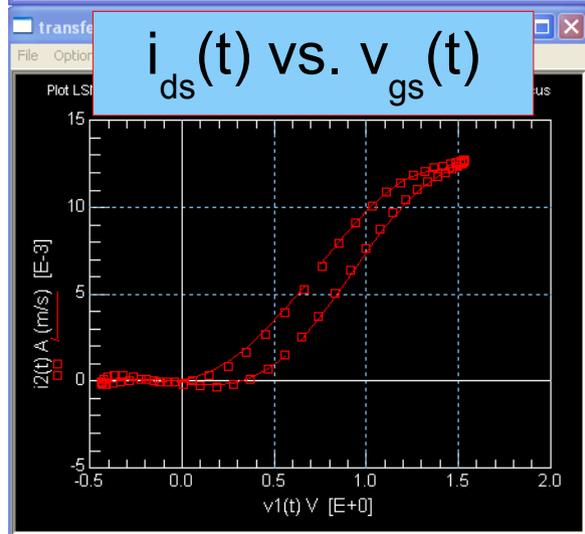
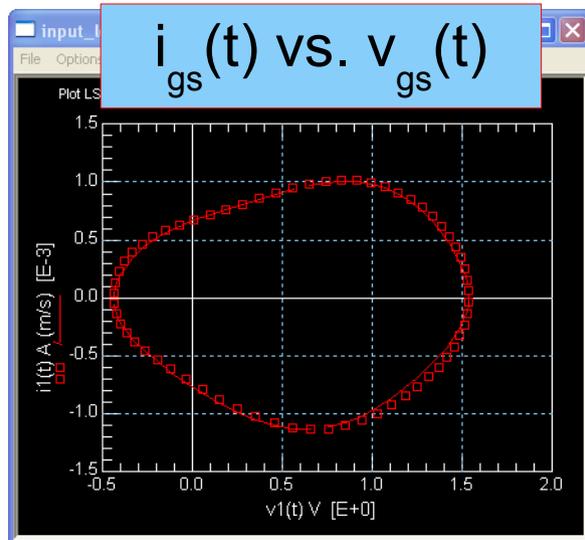
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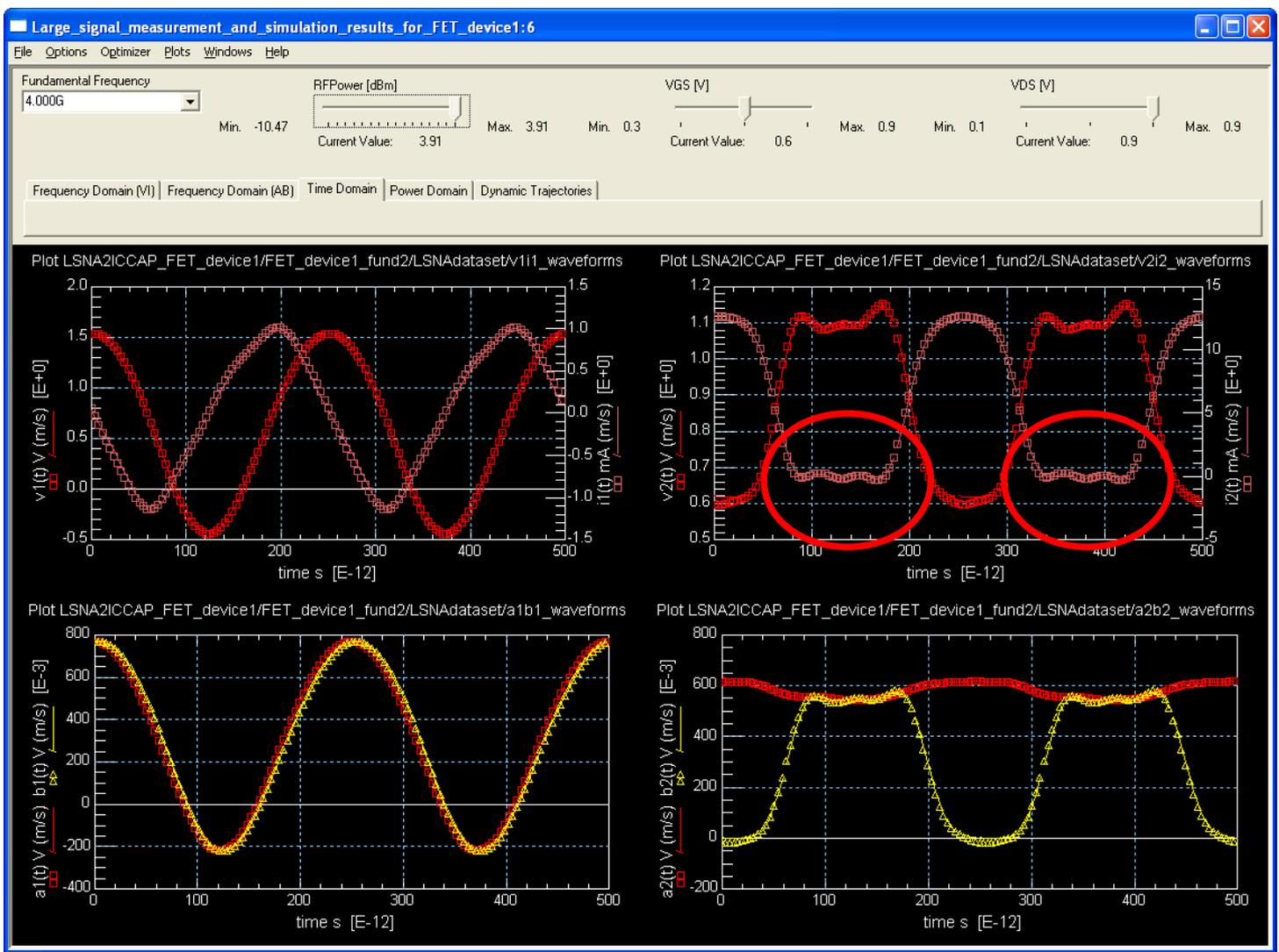
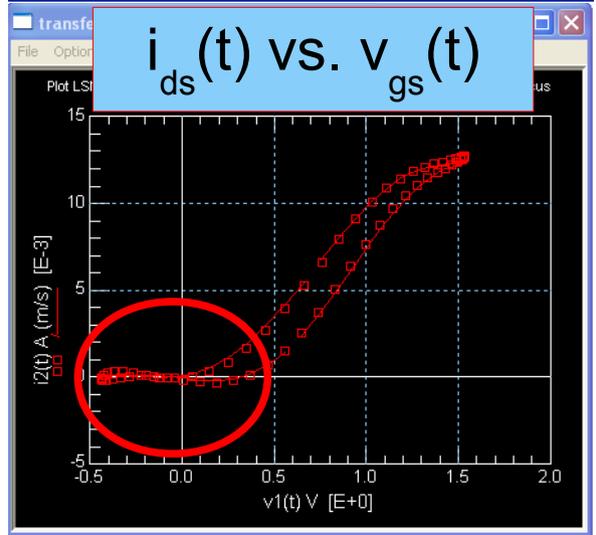
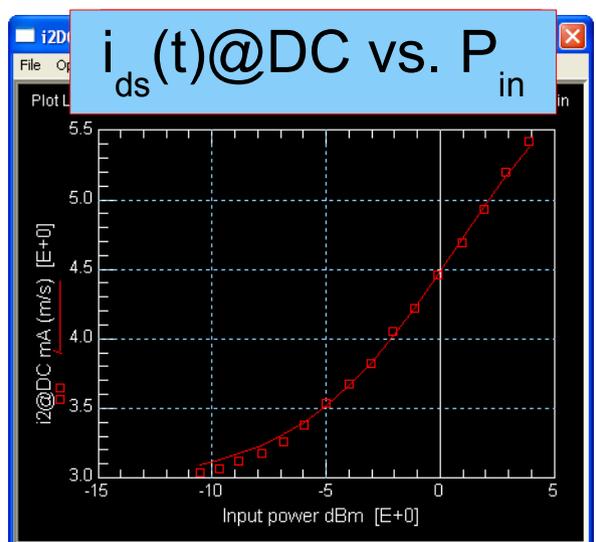
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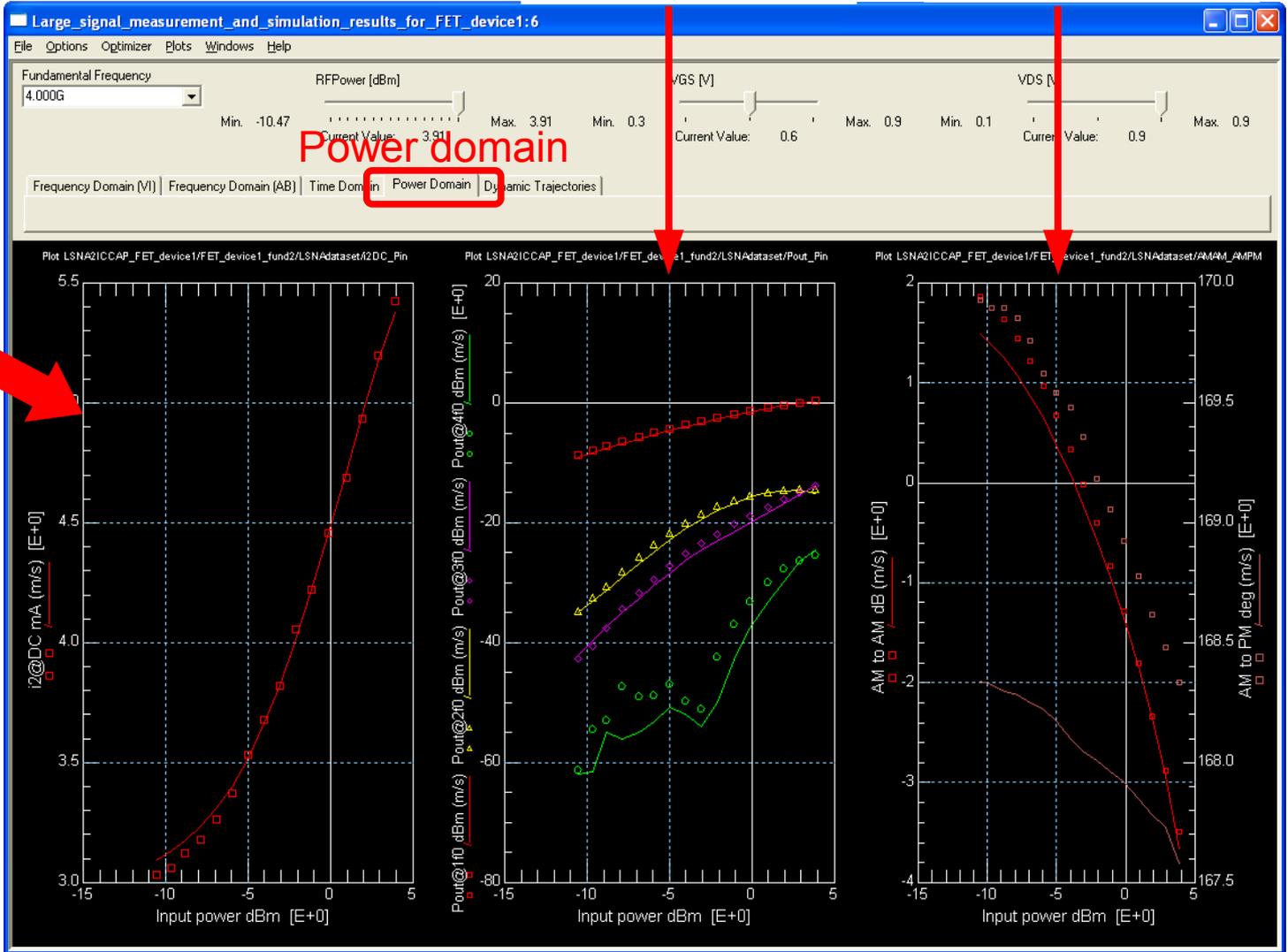
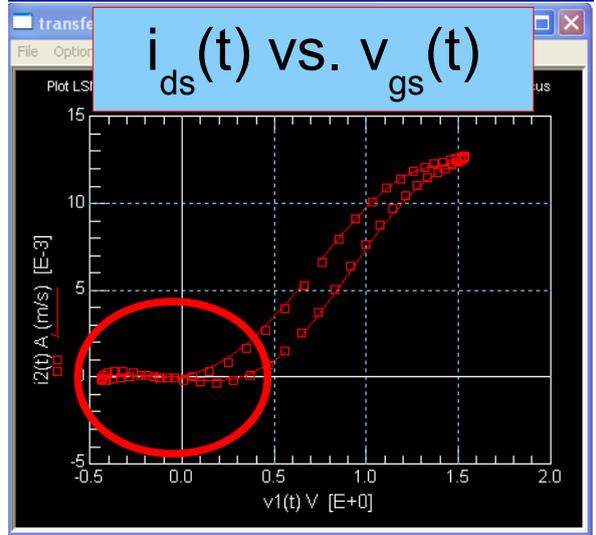
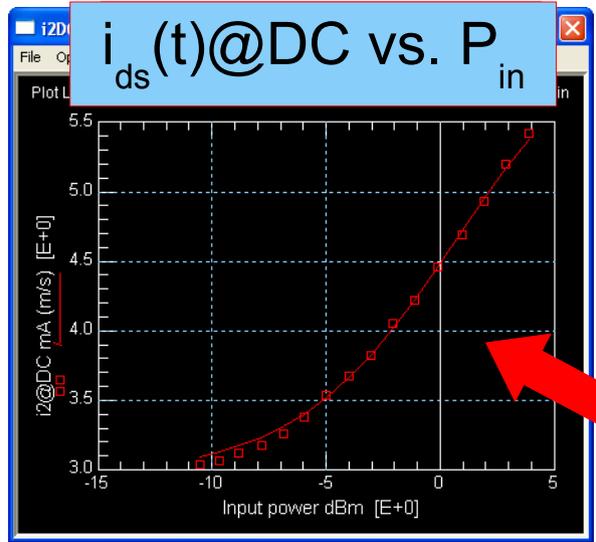
Self biasing effect

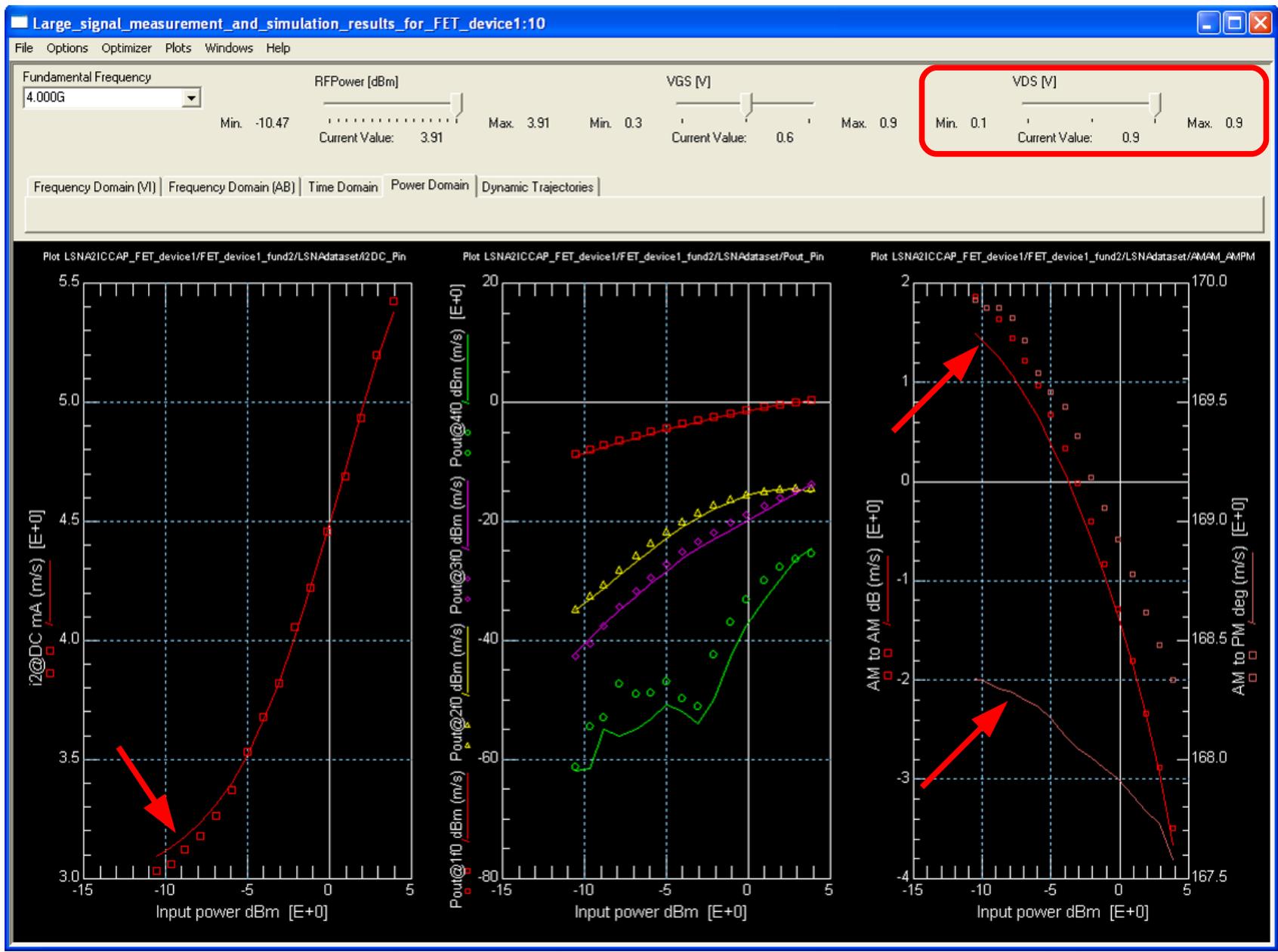


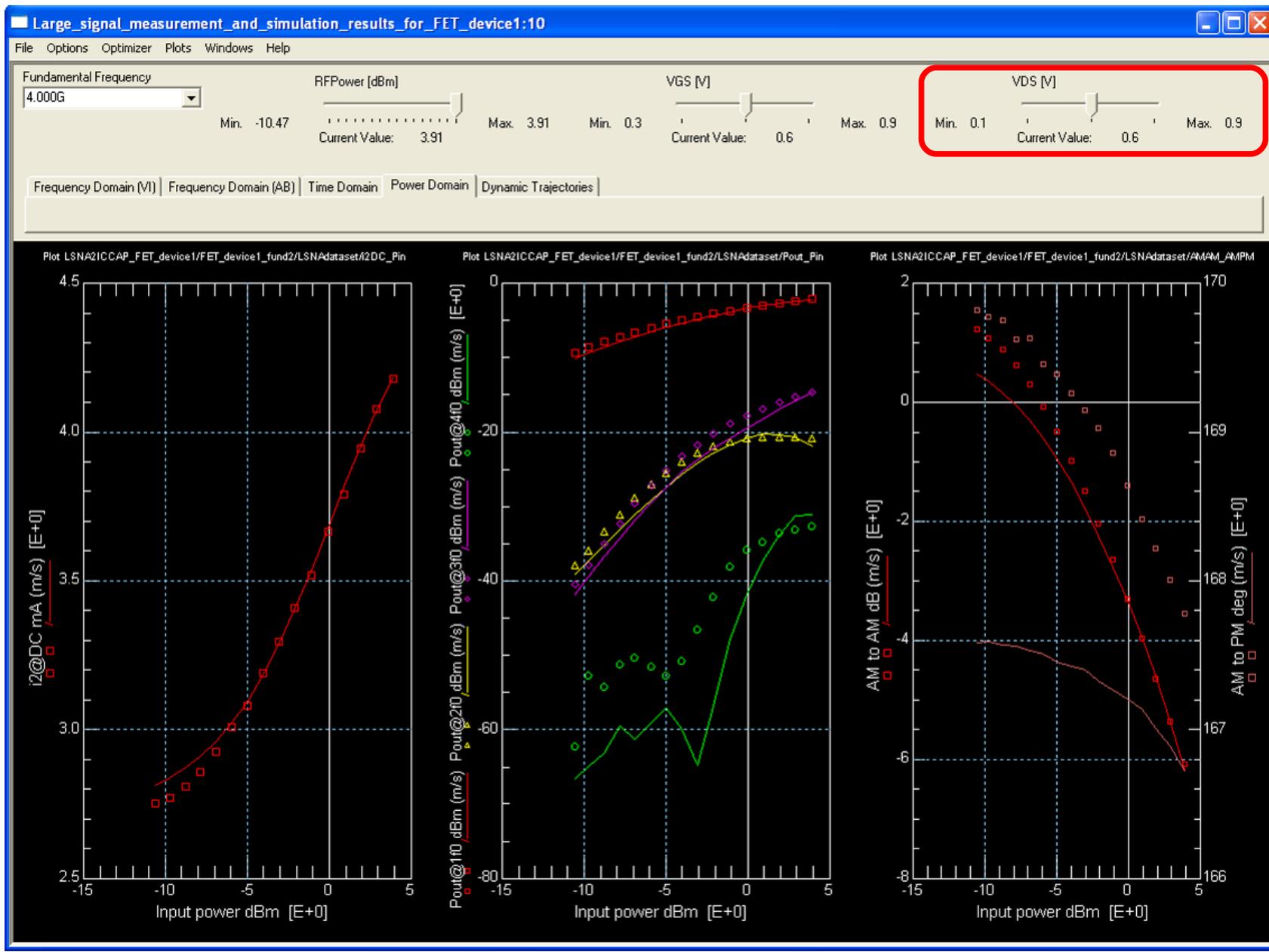
Self biasing effect

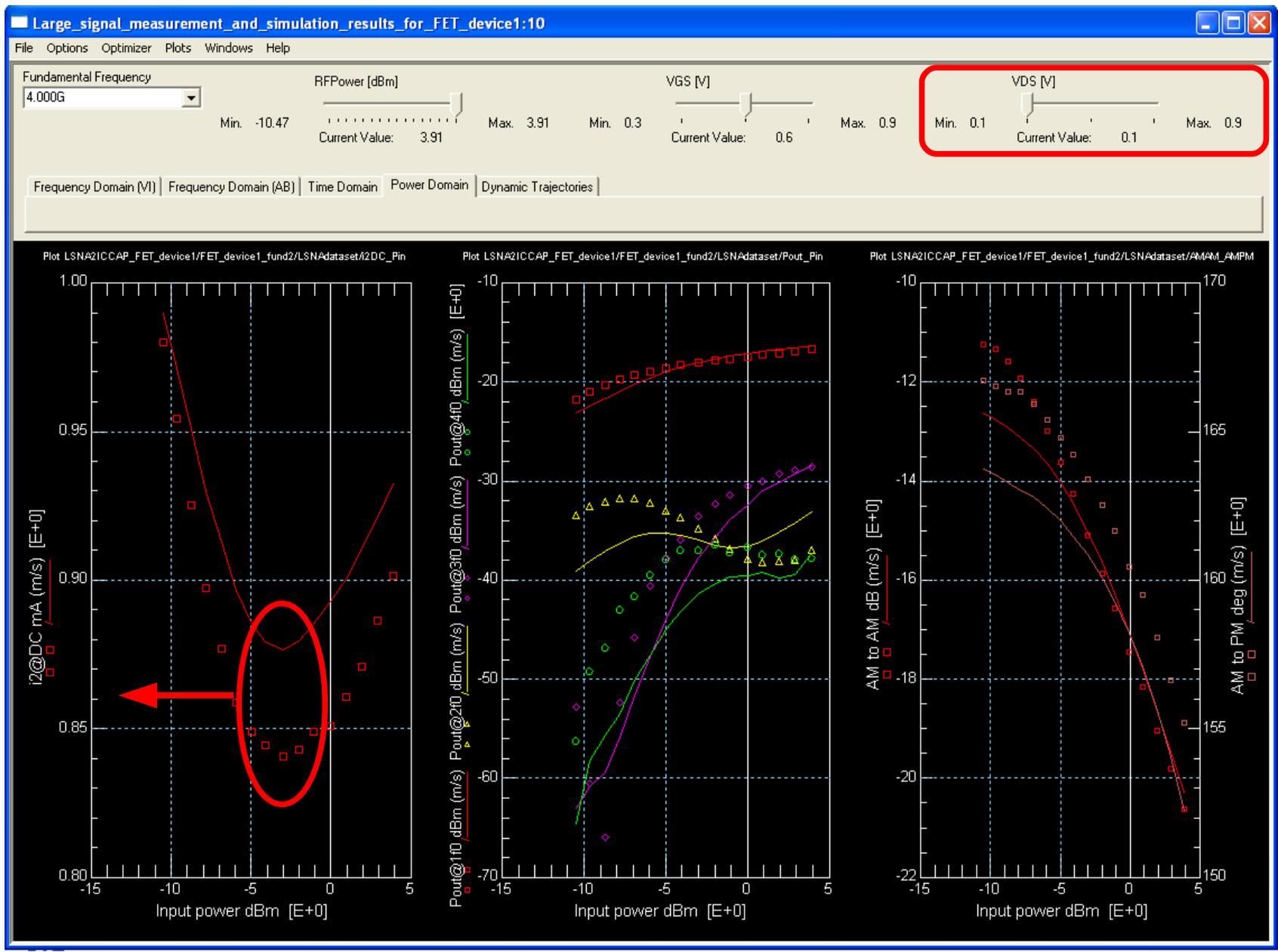
Harmonic distortion

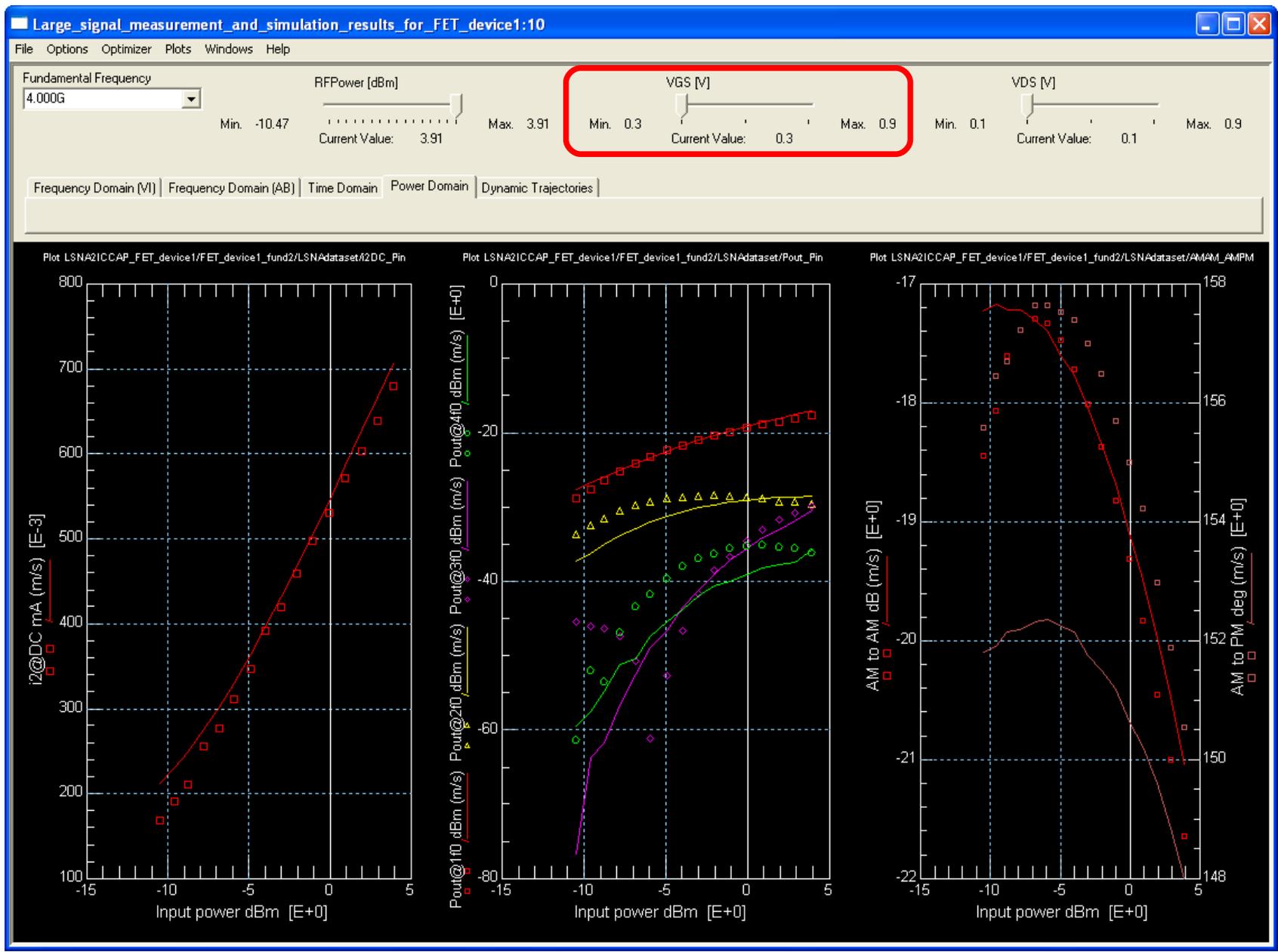
AM-AM
AM-PM

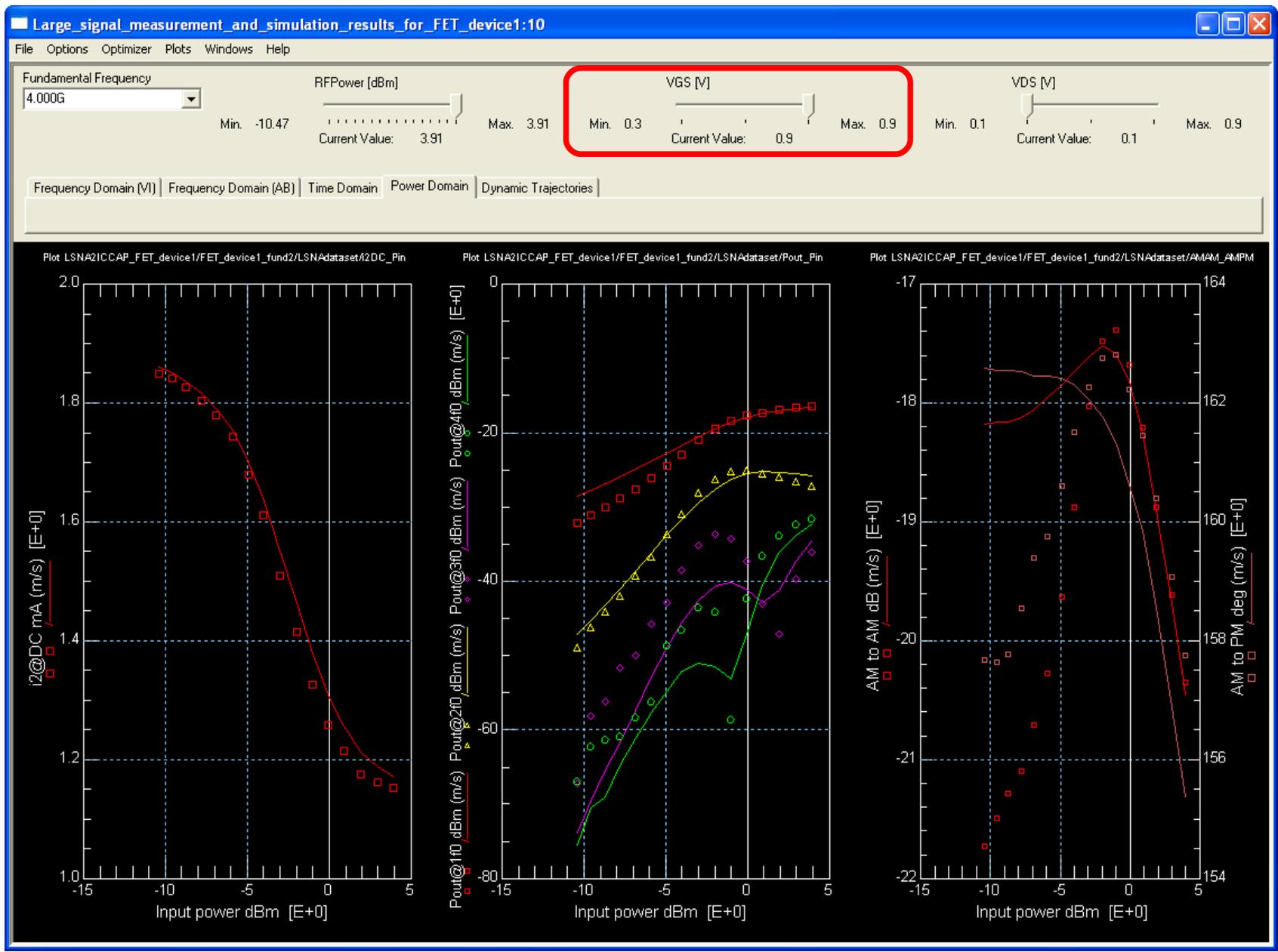


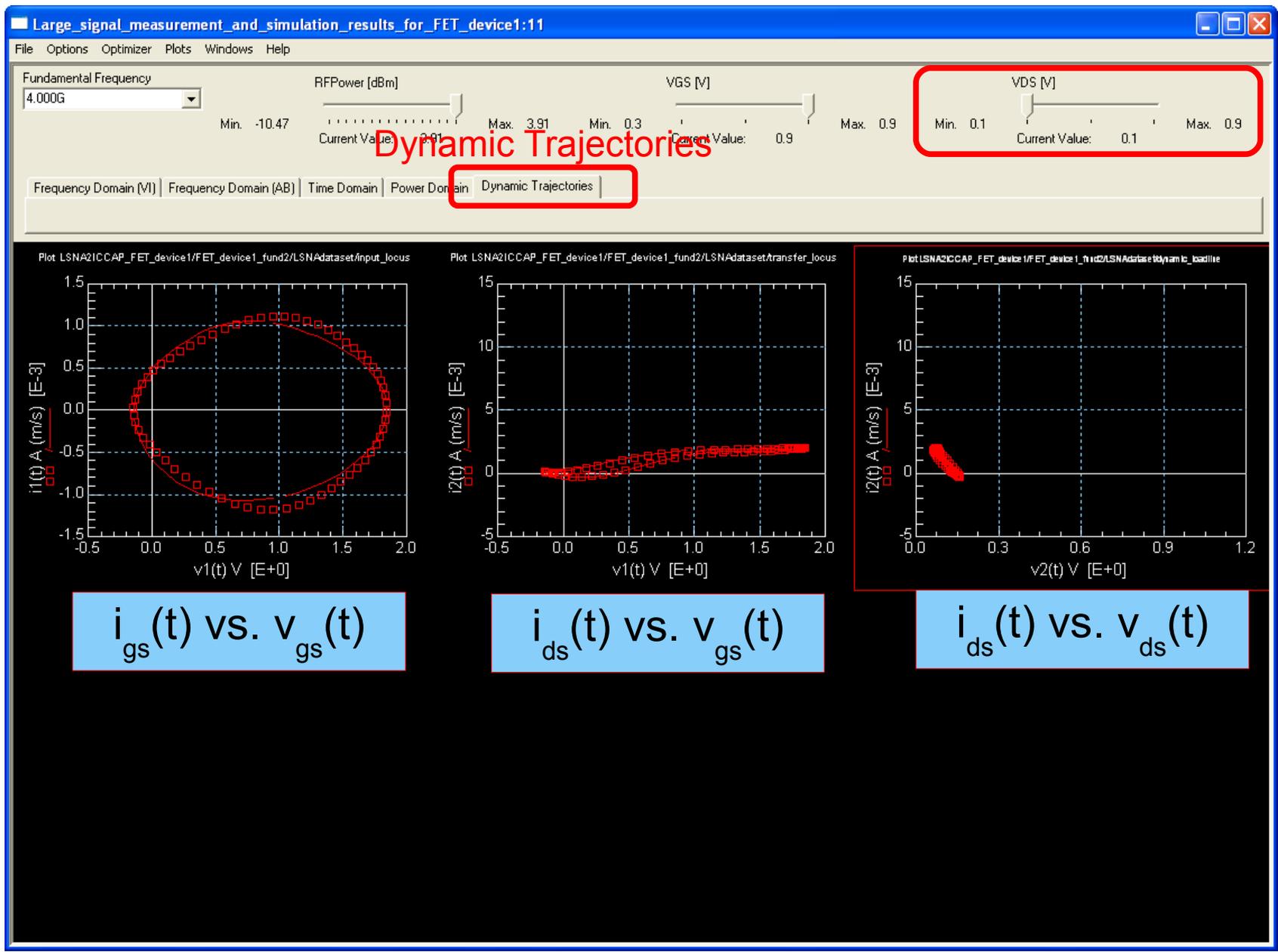


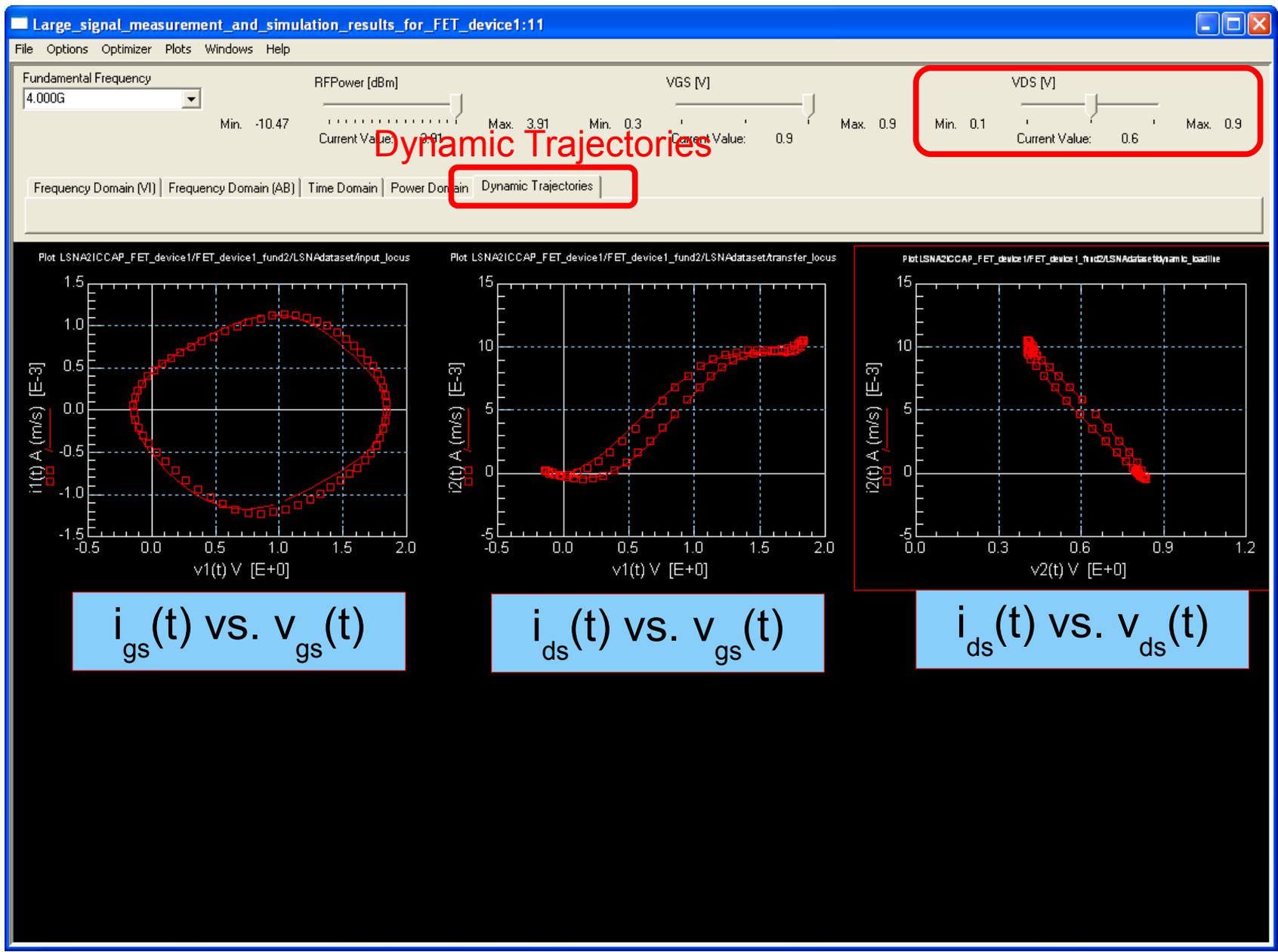


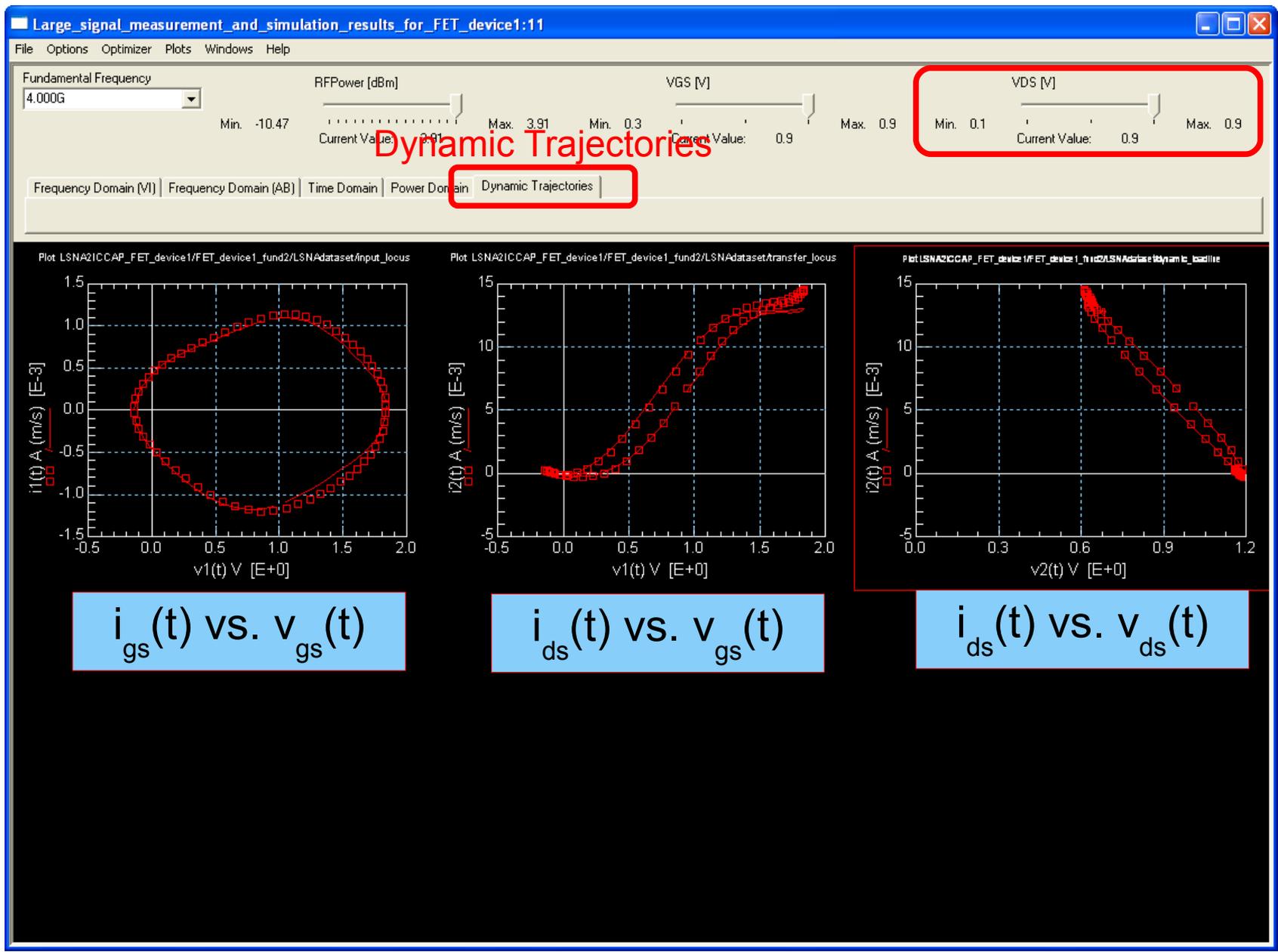


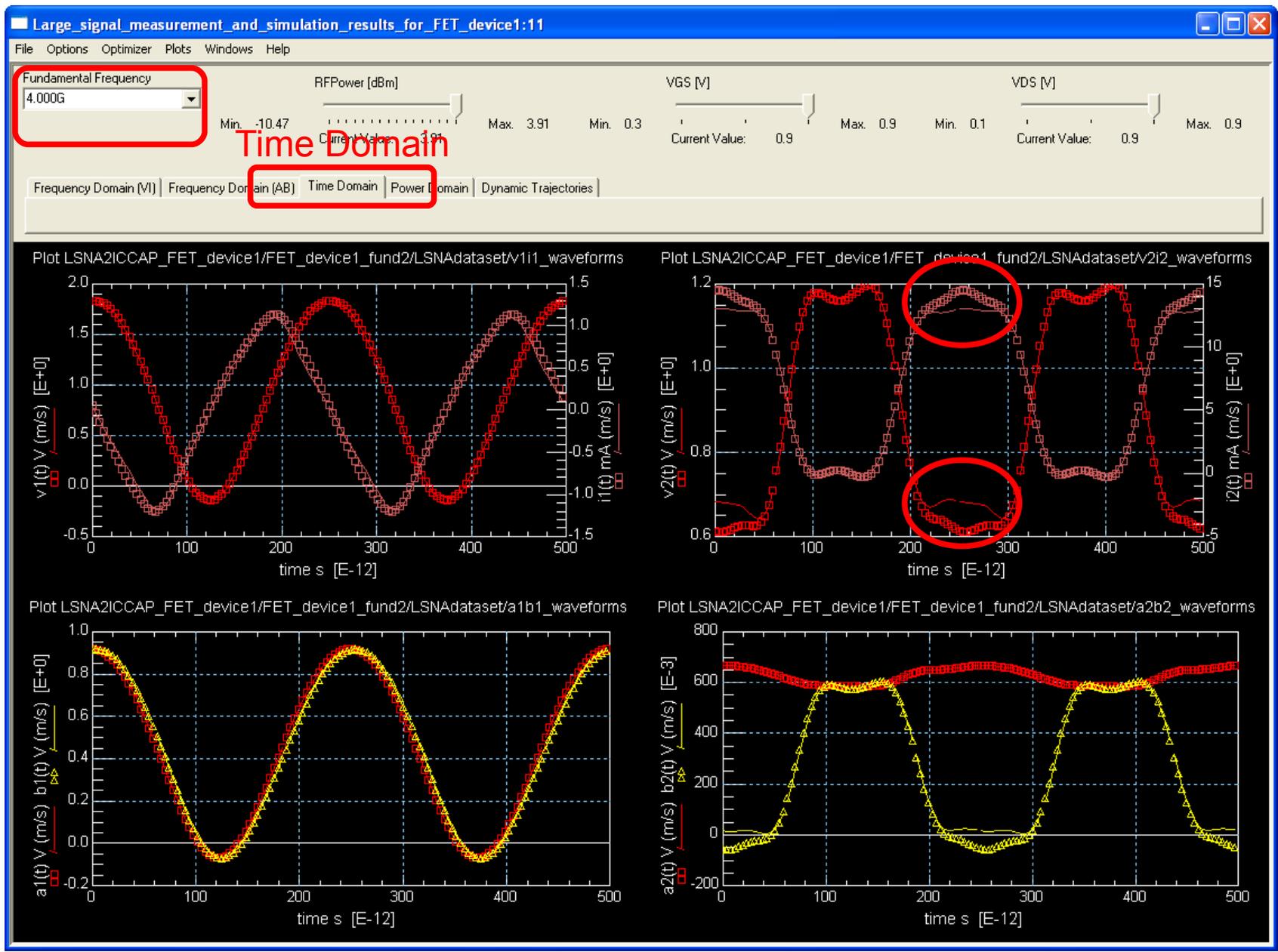


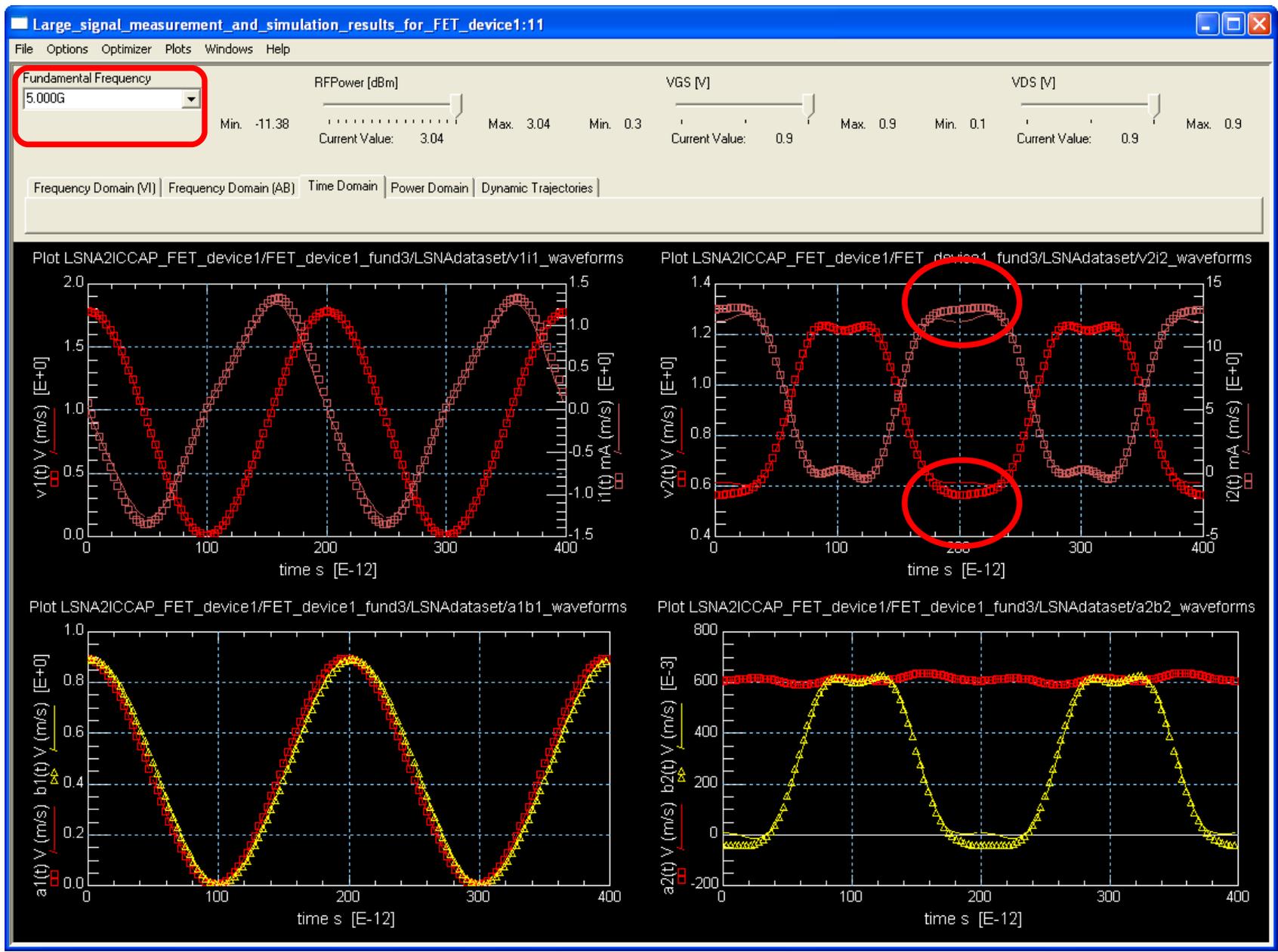


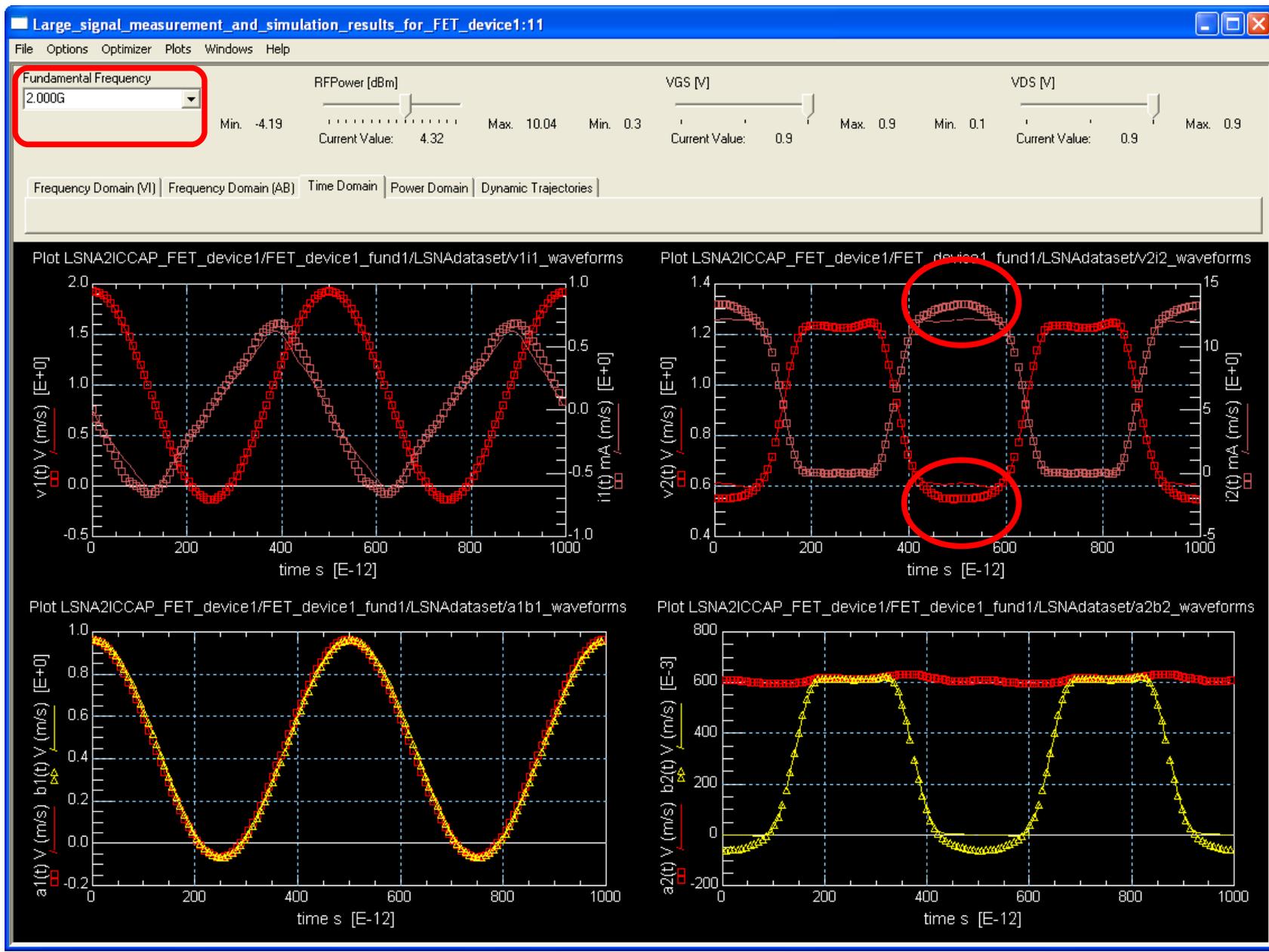


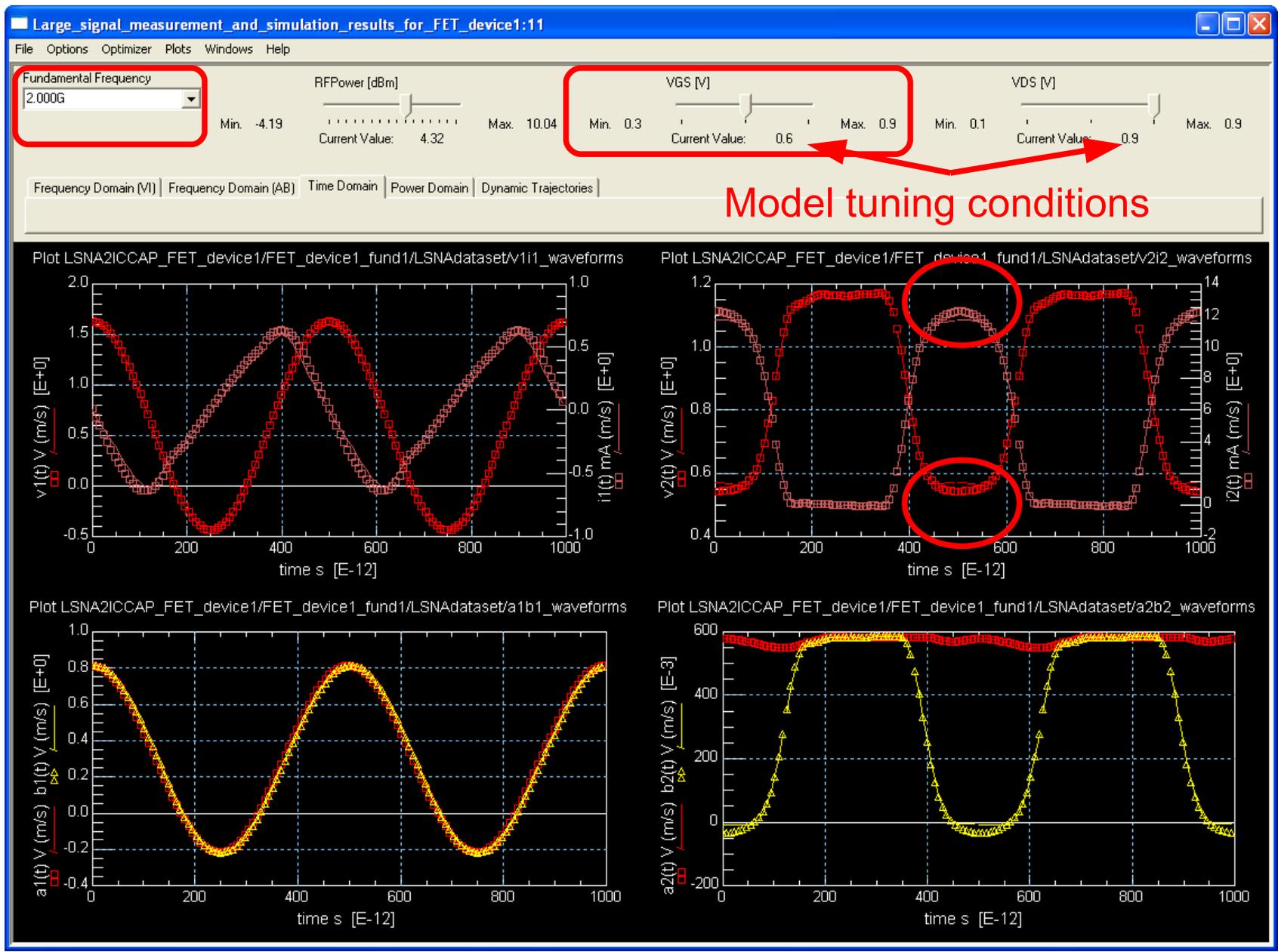












- Large-signal measurements + device modeling program =
 - **Complete** large-signal device characterization and model accuracy assessment under realistic signals,
 - **Simple access** and **improved usability** of the measured data,
 - Model **comparison** and **optimization**.